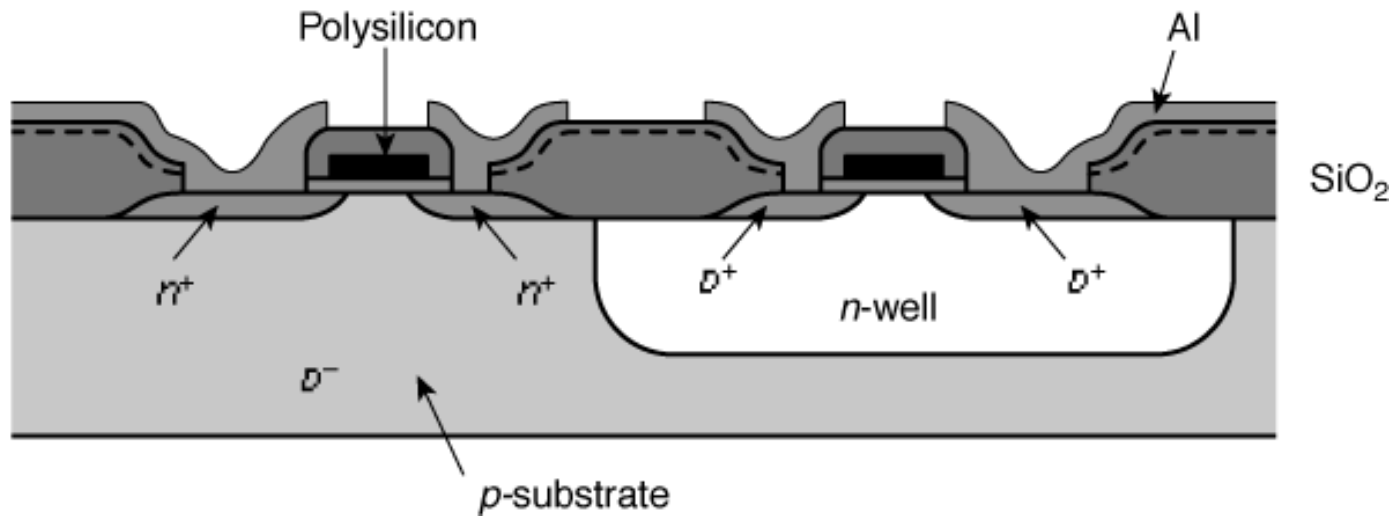


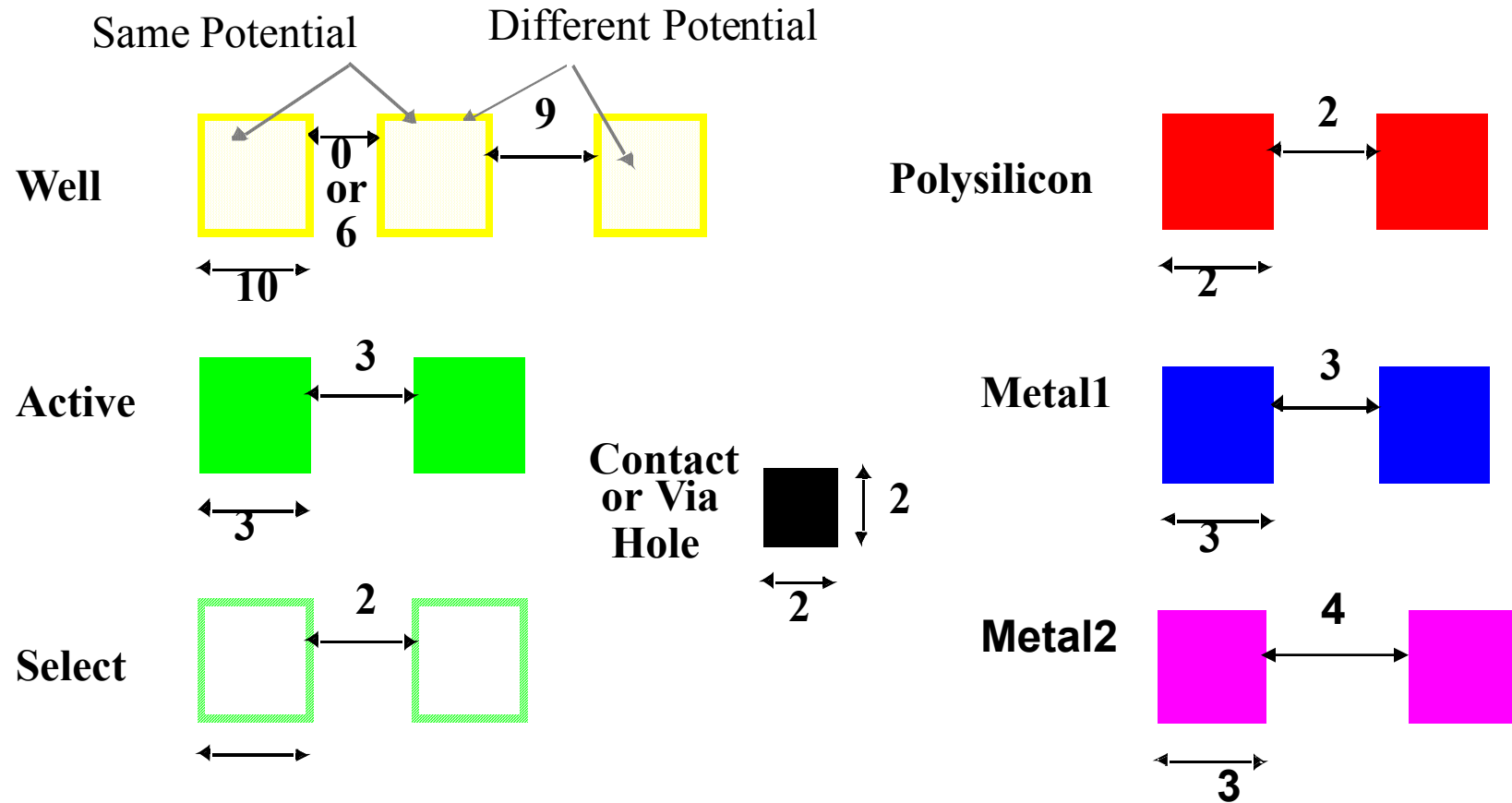
CMOS Process



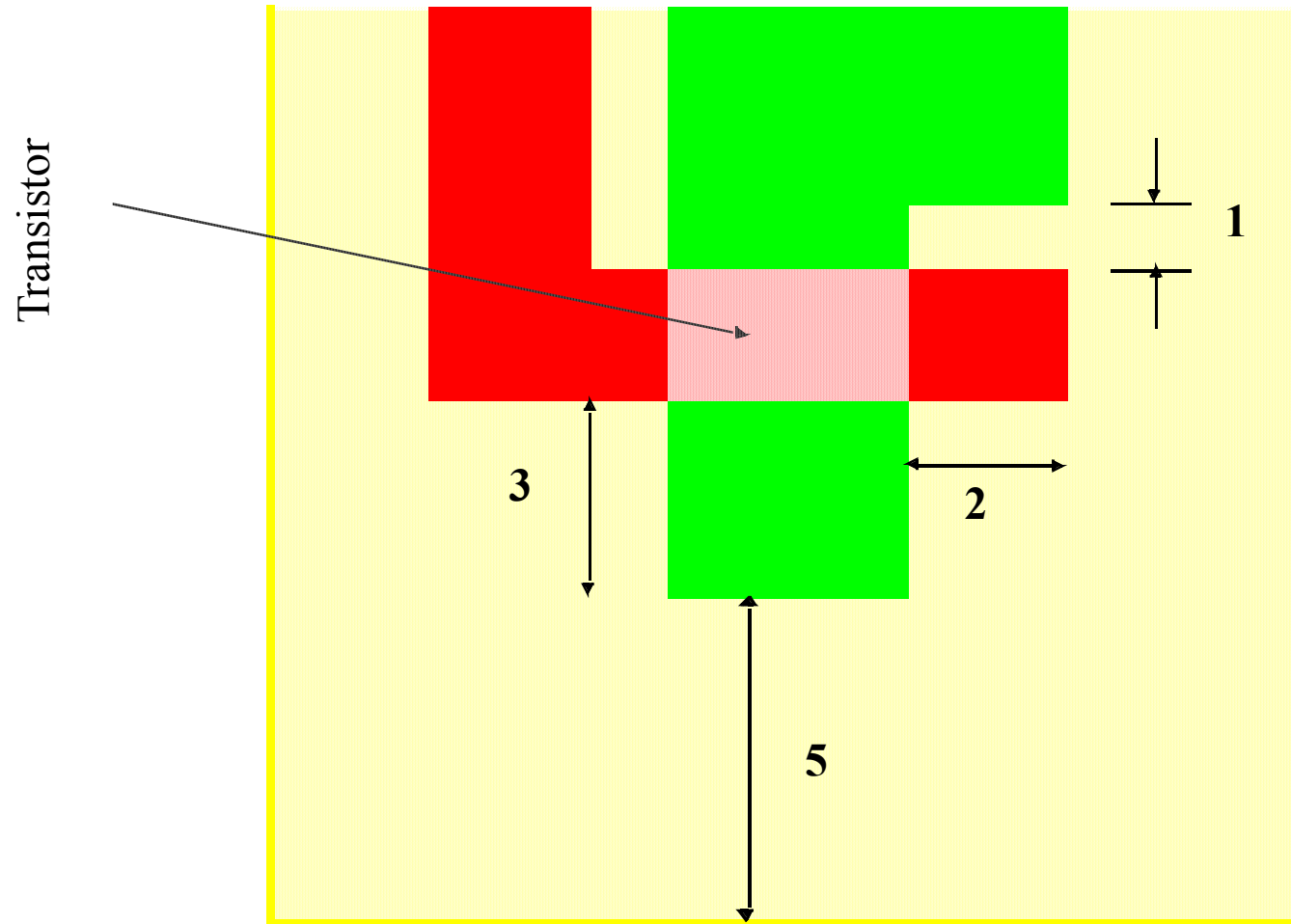
Design Rules

- Interface between designer and process engineer
- Guidelines for constructing process masks
- Unit dimension: Minimum line width
 - scalable design rules: lambda parameter
 - absolute dimensions (micron rules)

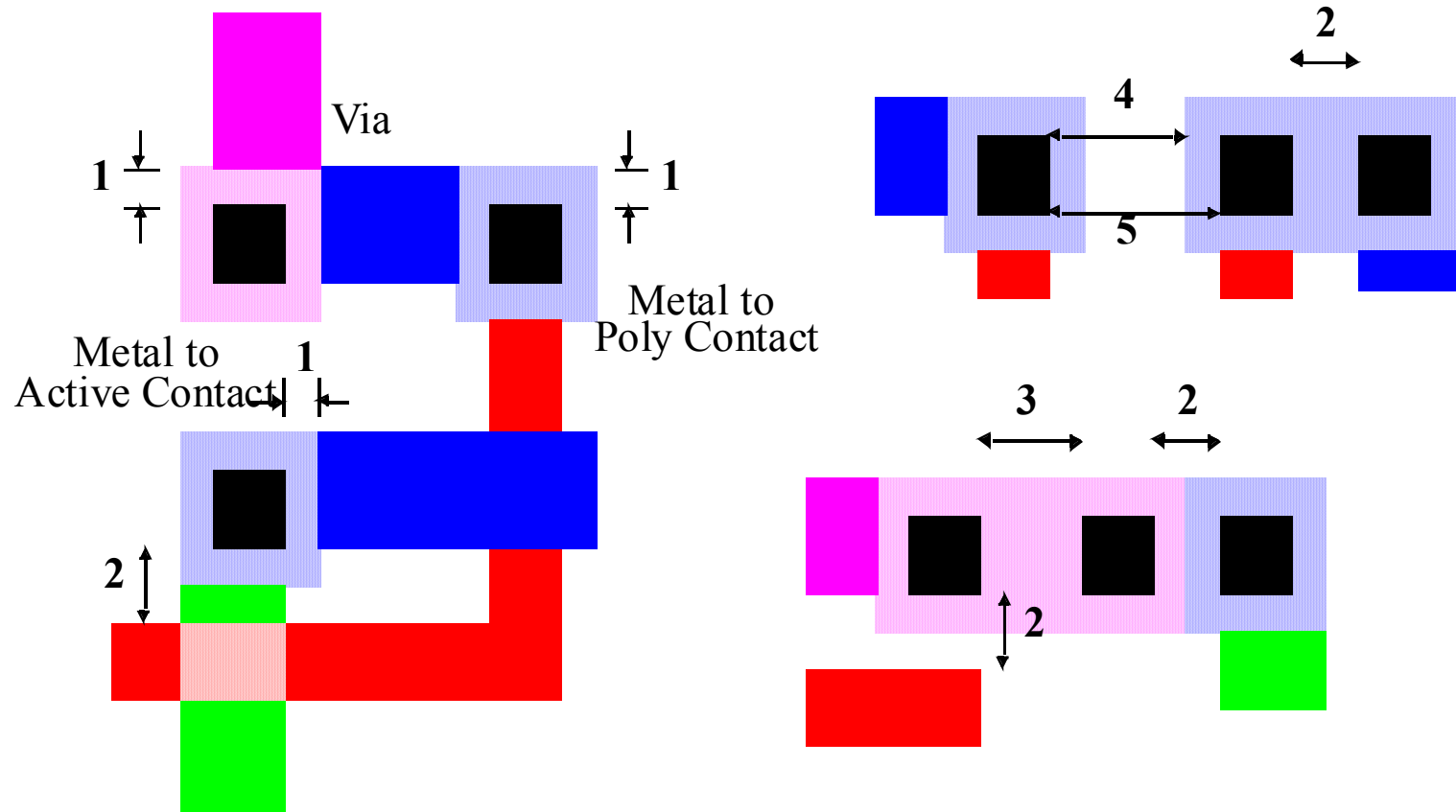
Intra-Layer Design Rules



Transistor Layout



Vias and Contacts



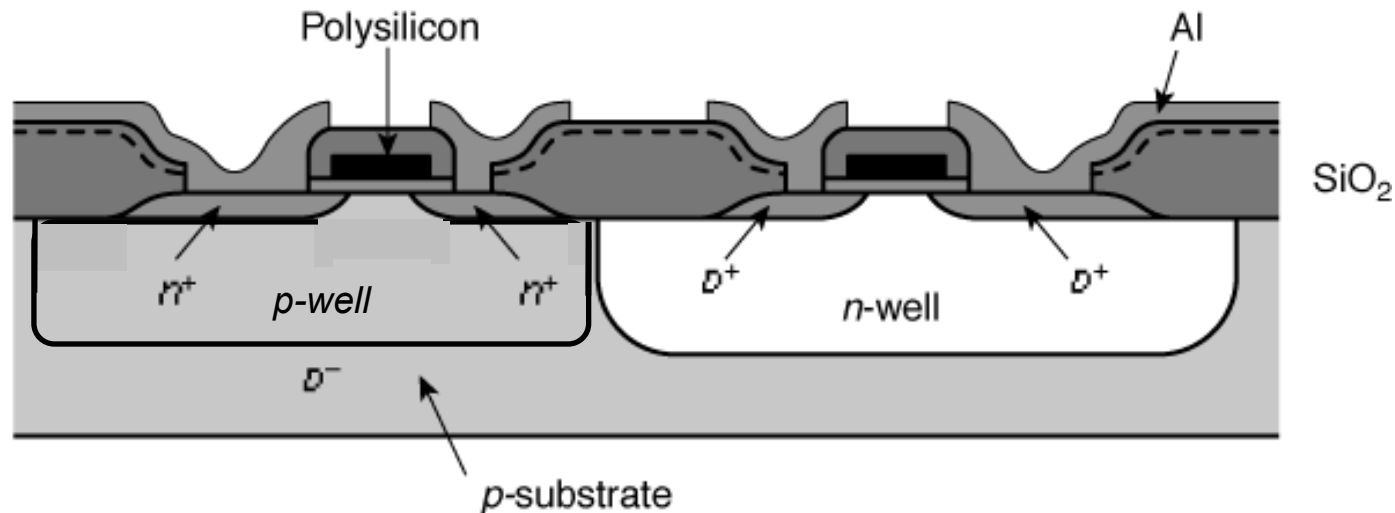
45nm Process

| Layer | Purpose |
|----------|---|
| Active | Active for NMOS and PMOS |
| Poly | Polysilicon line for NMOS/PMOS |
| Nwell | Nwell region for PMOS |
| Pwell | Pwell region for NMOS |
| Nimplant | Implant N+ to source/drain for NMOS |
| Pimplant | Implant P+ to source/drain for PMOS |
| Contact | Contacts - connect Metal1 to Poly or active |
| vthg | General use threshold implant |
| vthh | High threshold implant |

45nm Process

| Layer | Purpose |
|---|---|
| Metal1 and Via1 | Metal 1 and Via 1 to connect Metal1 to Metal2 |
| Metal2 and Via2 | Metal 2 and Via 2 to connect Metal2 to Metal3 |
| Metal3 and Via3 | Metal 3 and Via 3 to connect Metal3 and Metal4 |
| Metal4 | Metal 4 |
| | |
| You should not need more than 4 levels of metals for the project | |

NFET – Process View



You need to identify the gate and source-drain -> Poly and Active

Poly-> gate,

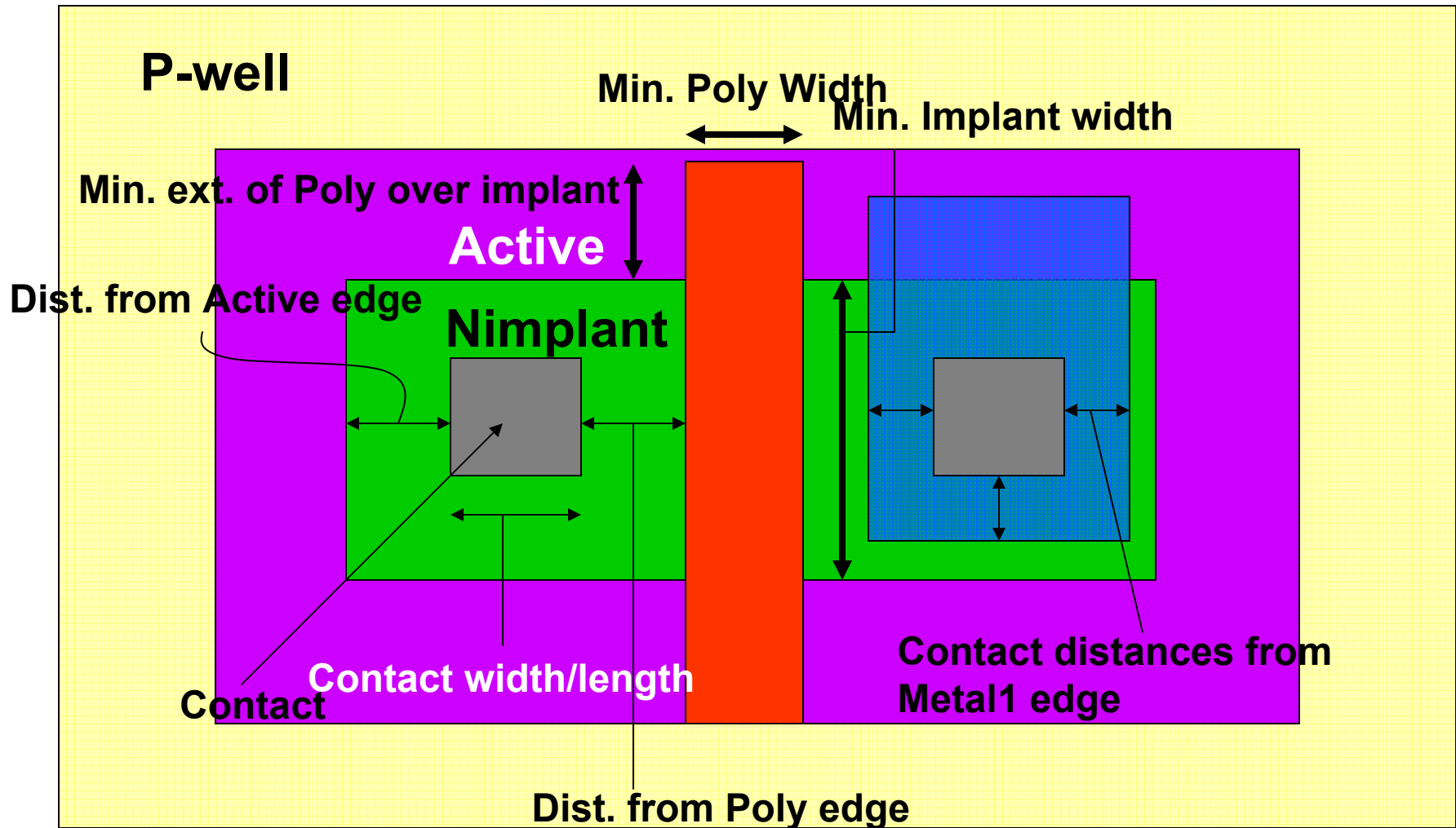
Active -> total diffusion area

nimplant -> N+ implant for Source/Drain

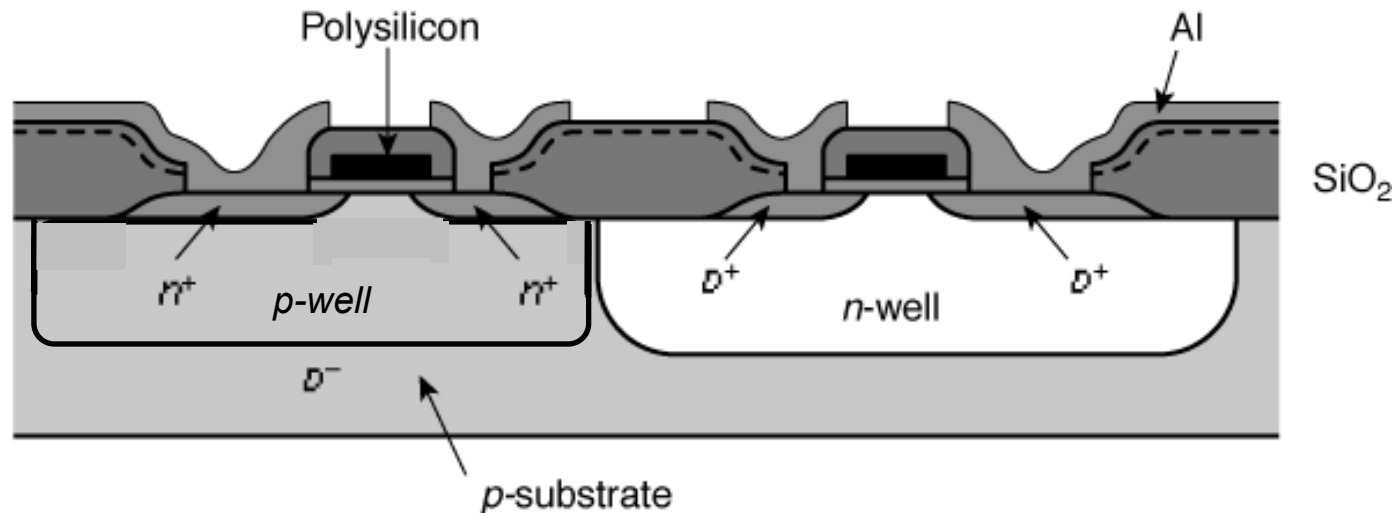
Poly & nimplant overlap -> Transistor

You need to add P-well contact

Create NFET



PFET – Process View



You need to identify the gate and source-drain -> Poly and Active

Poly -> gate,

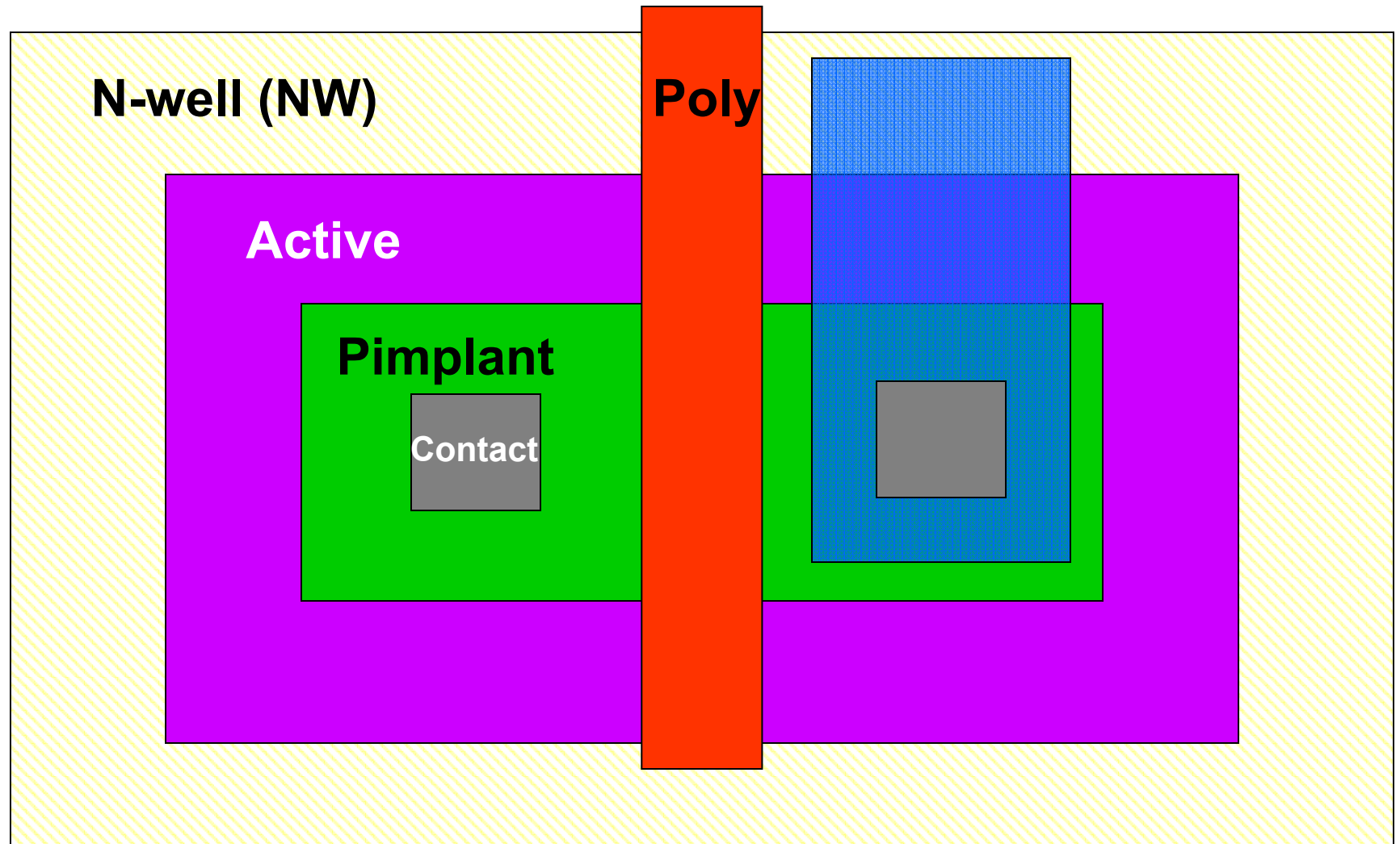
Active -> total diffusion area

pimplant -> P+ implant for Source/Drain

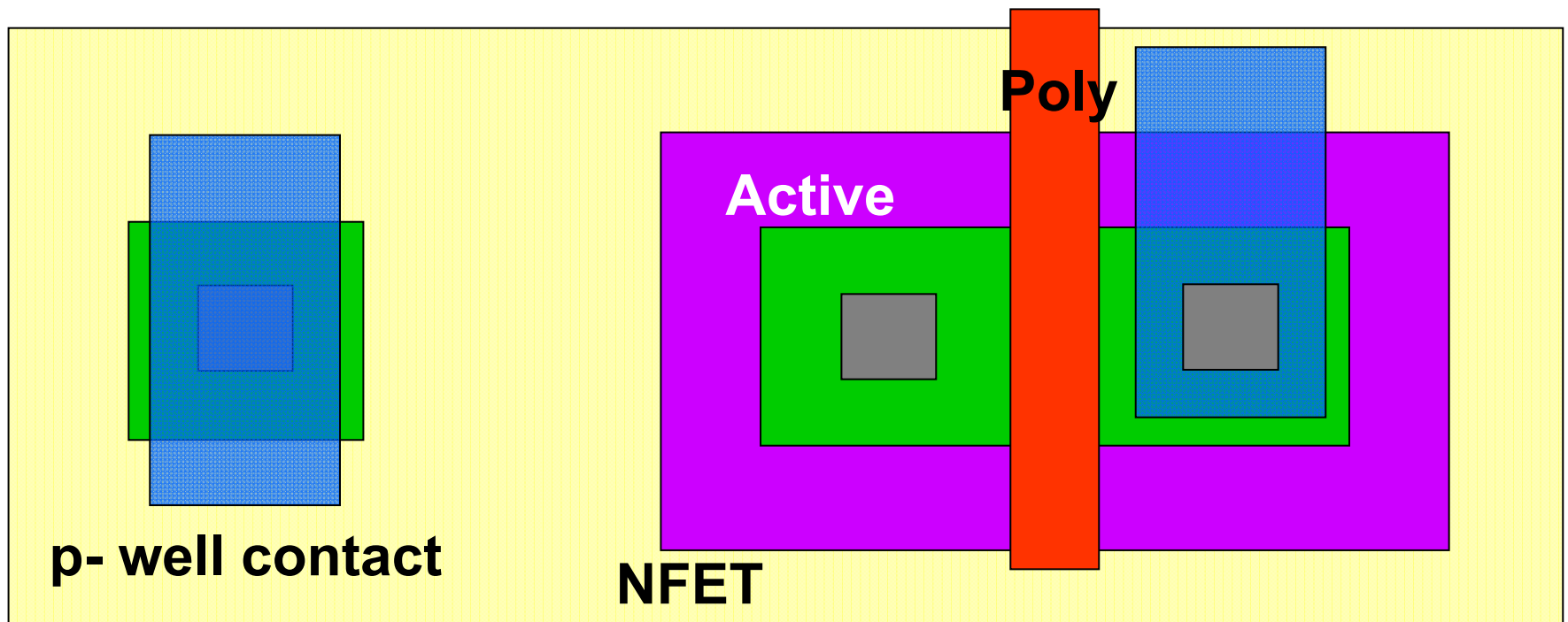
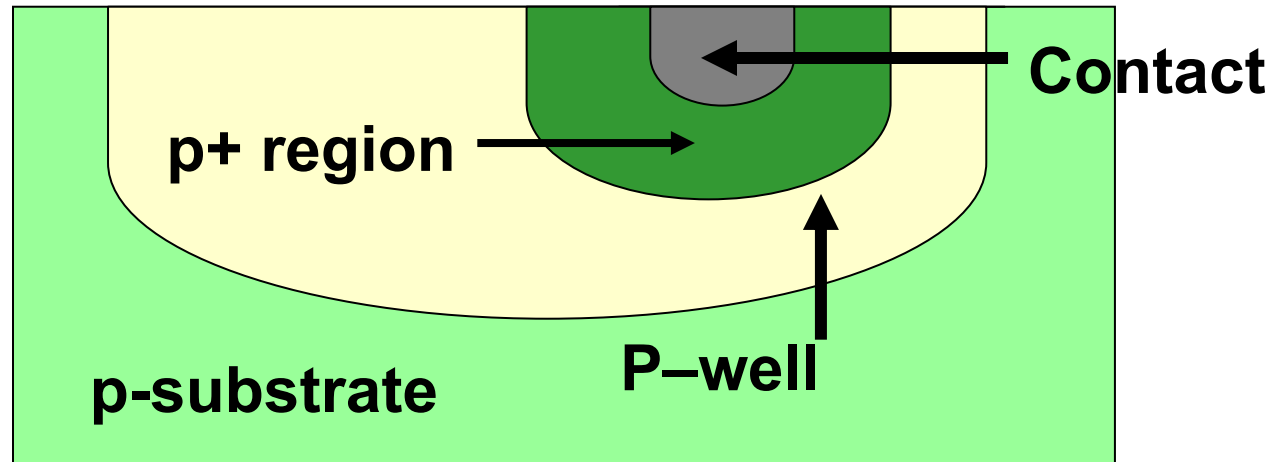
Poly & pimplant overlap -> Transistor

You need to add N-well contact

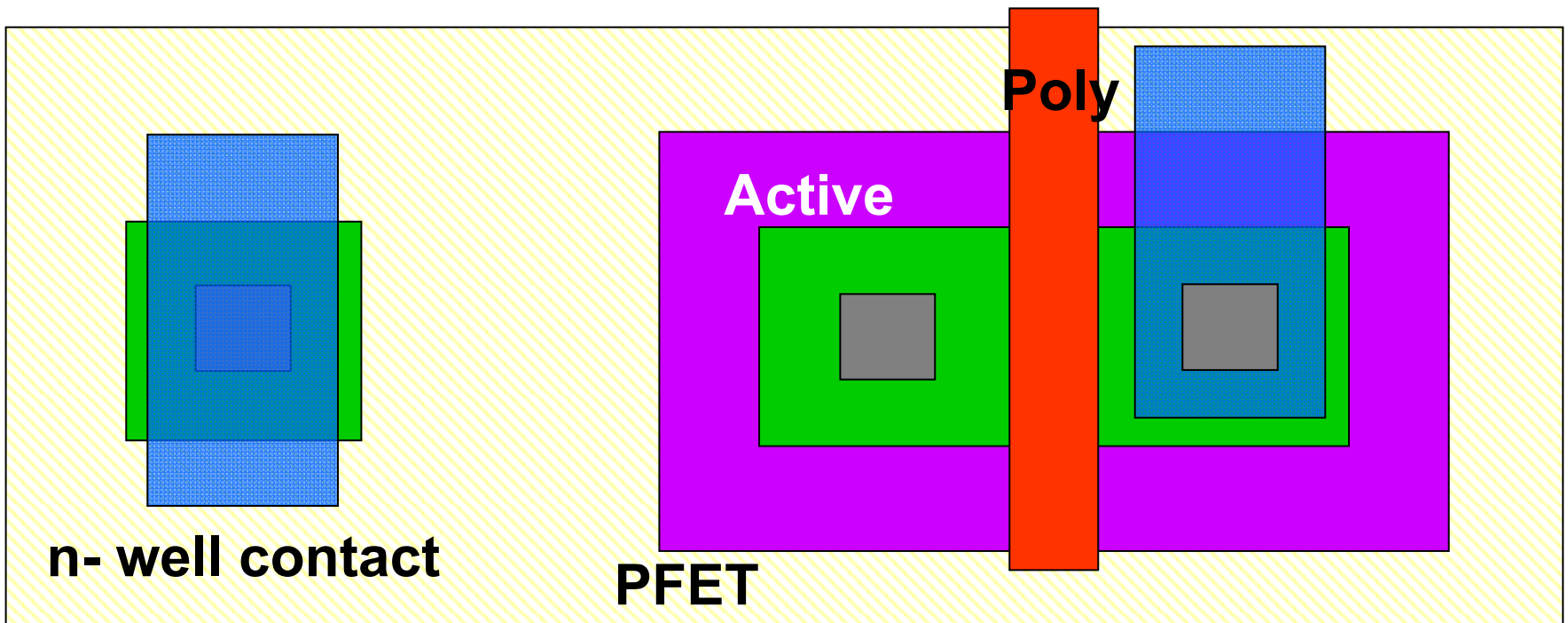
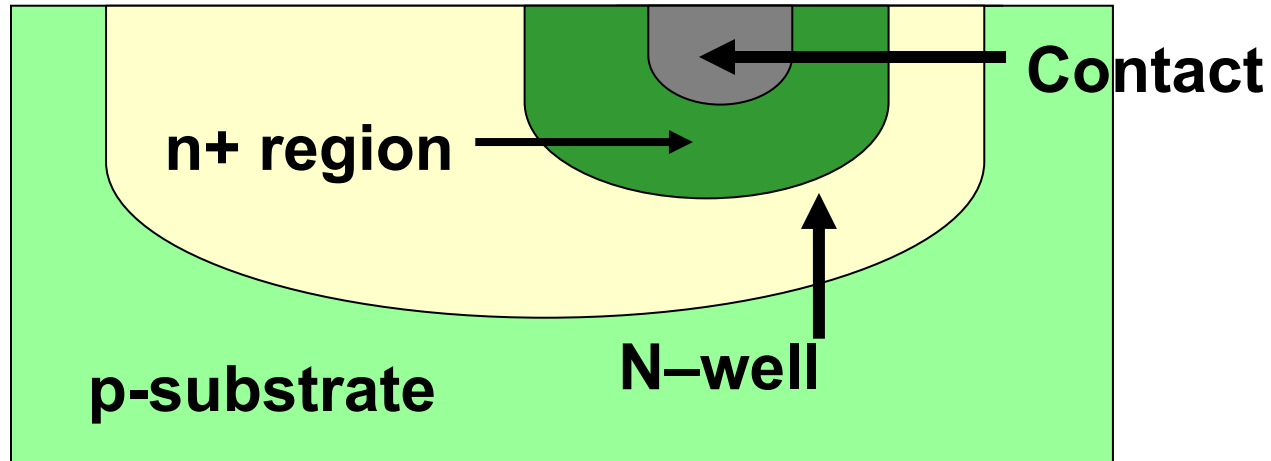
Create PFET



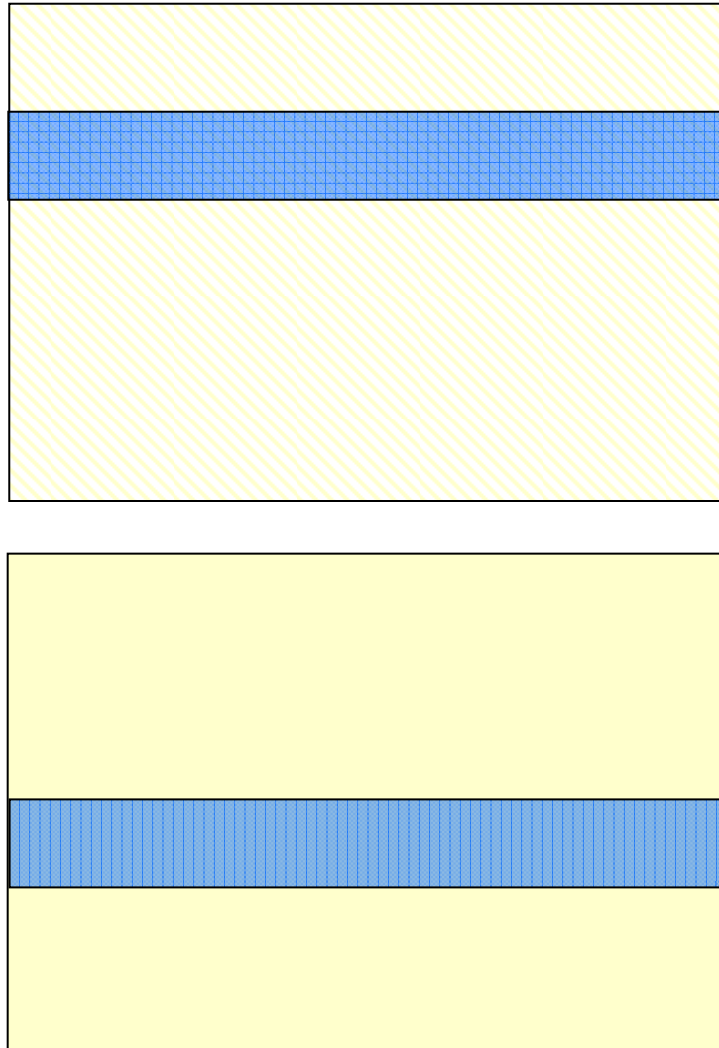
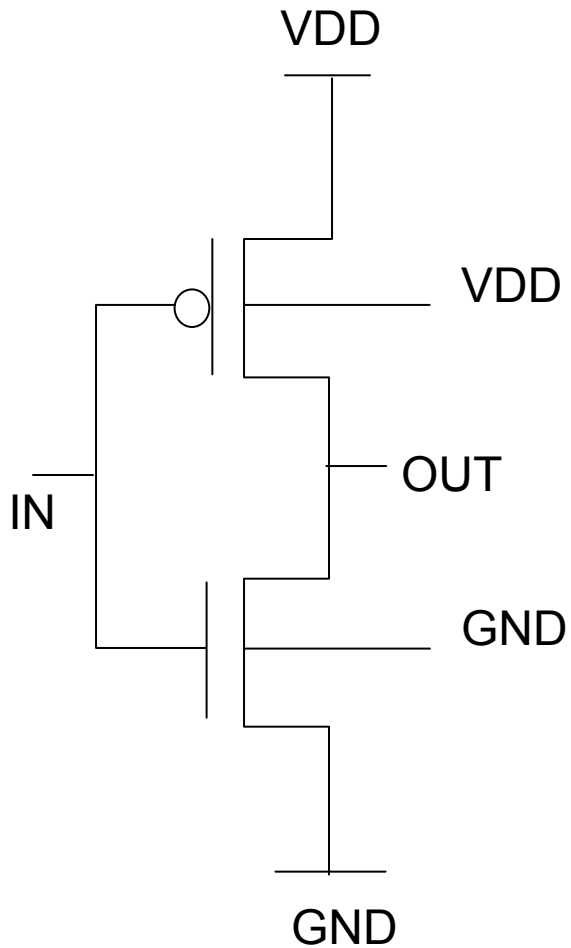
NFET with p-well Contact



PFET with n-well Contact

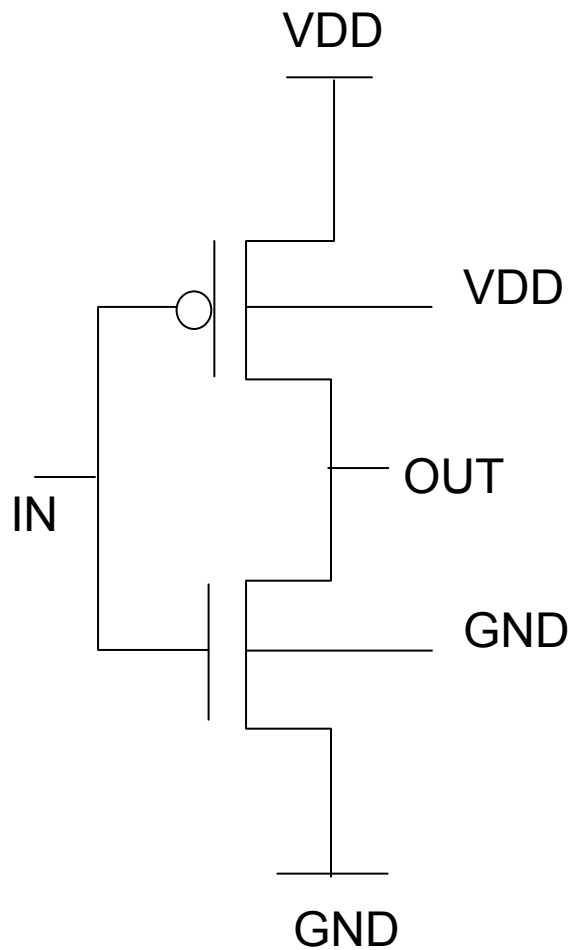


Create INVERTER

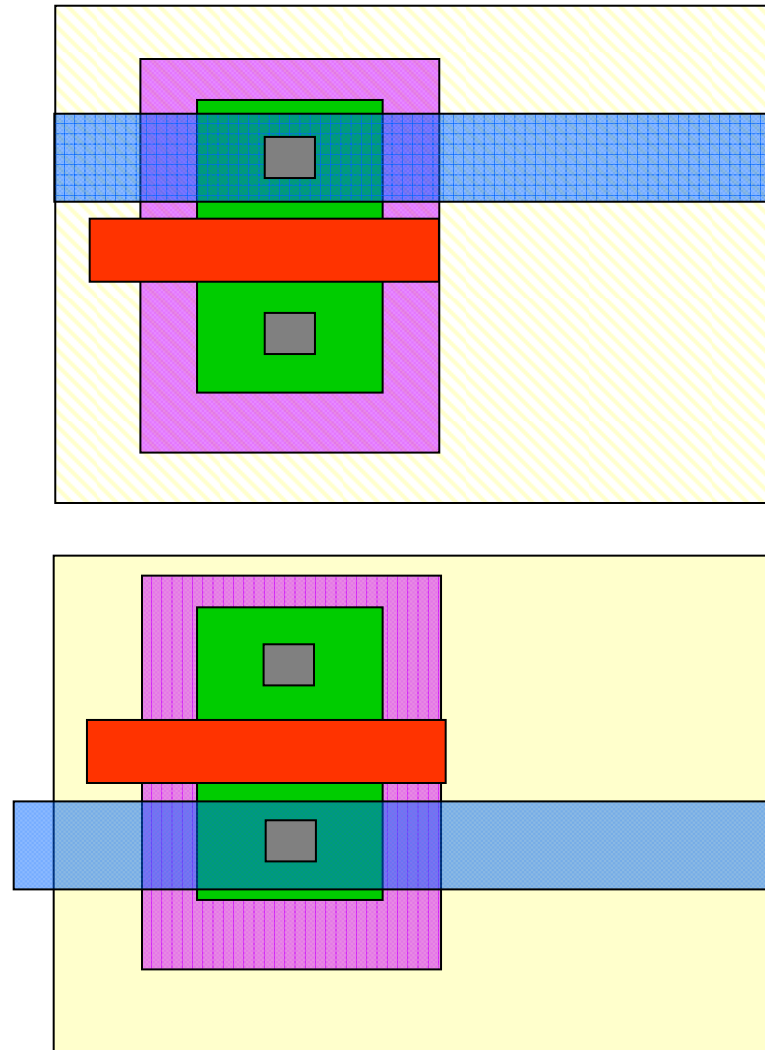


Set pitch of the cell using the power and ground buses.

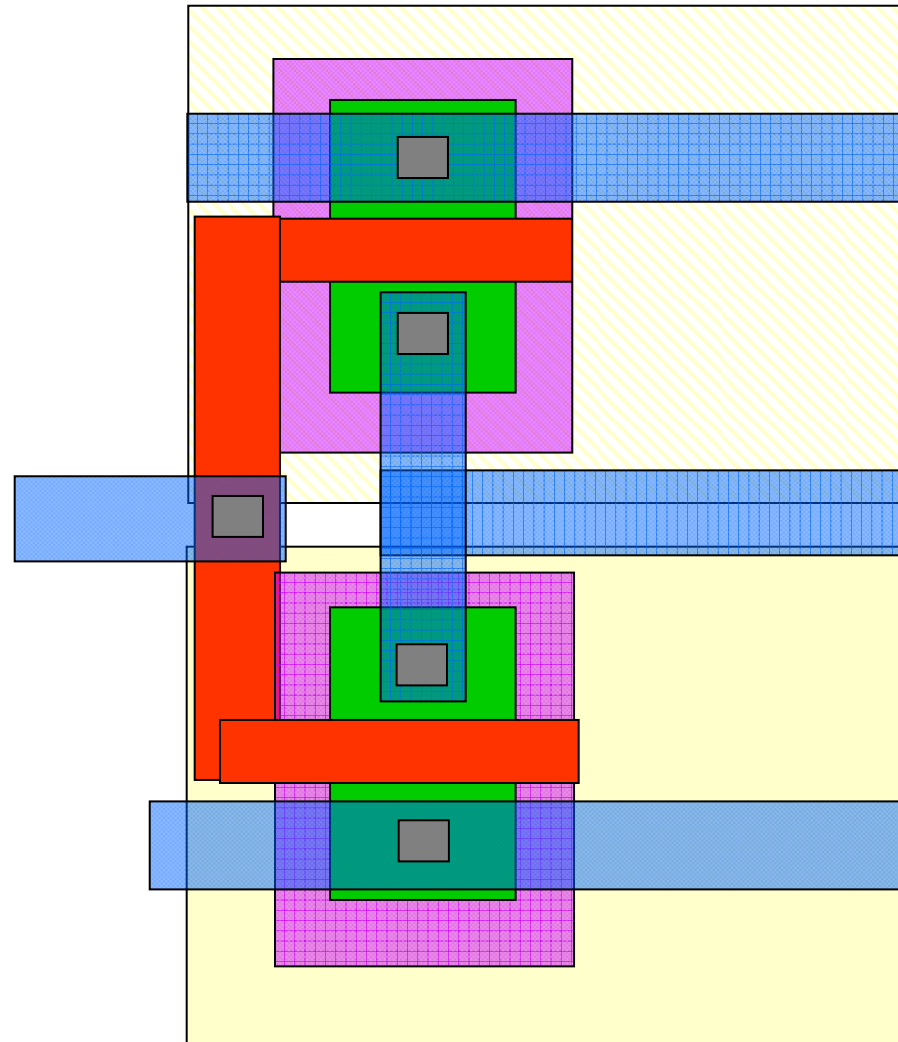
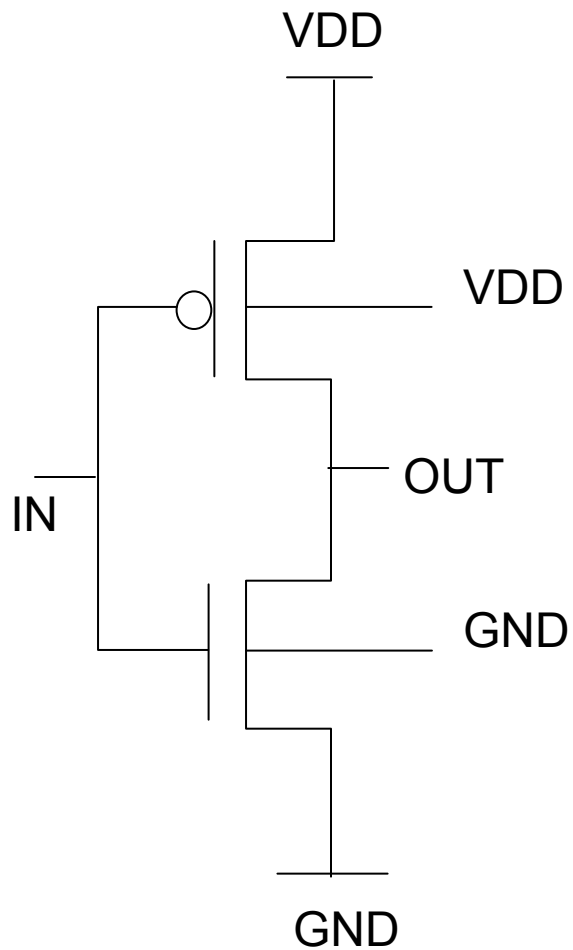
Create INVERTER



Add the transistors

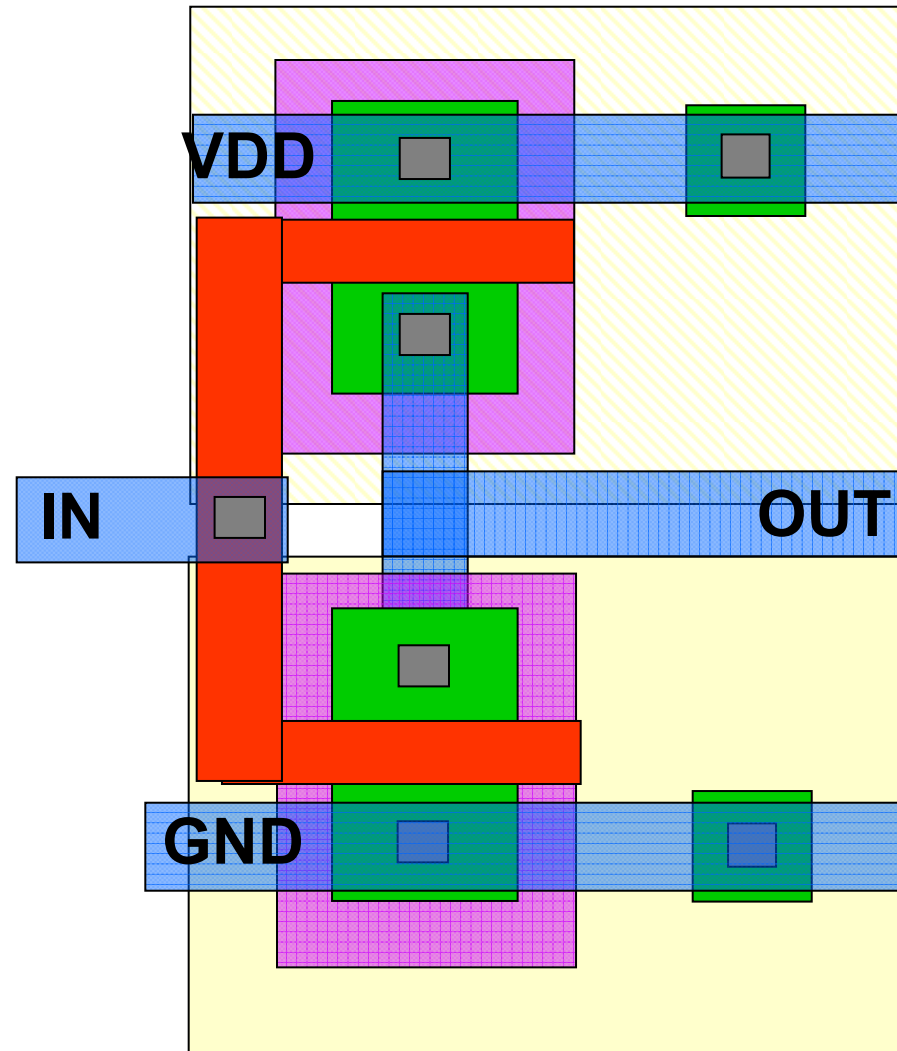
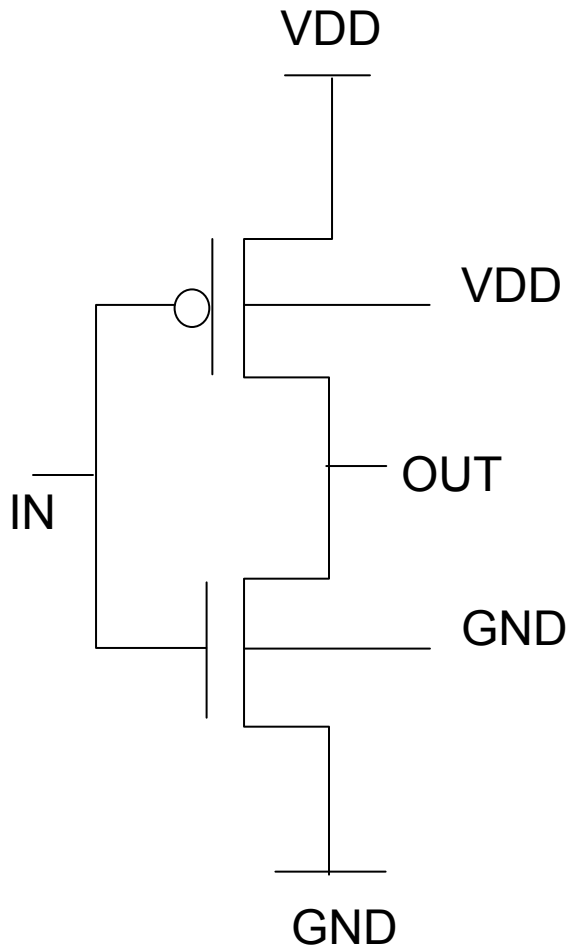


Create INVERTER



Connect the input/output lines

Create INVERTER



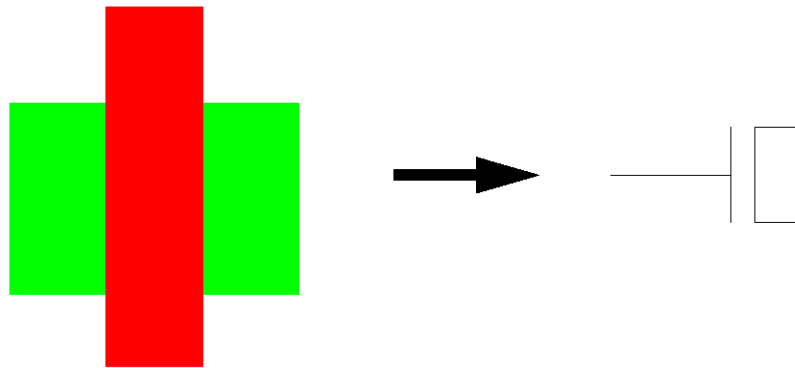
Add the p-well and n-well contacts

Design Error Check

- Design Rule Checker (DRC) –
 - Check whether design has validated any design rules
 - Ensures ‘manufacturability of design’
- Layout vs Schematic (LVS)
 - Ensures your layout matches with your schematic
 - Checks for shorts opens etc. in layout
 - Transistors and wire connections

Design Extraction

- **Circuit extraction extracts a schematic representation of a layout, including transistors, wires, and possibly wire and device resistance and capacitance.**



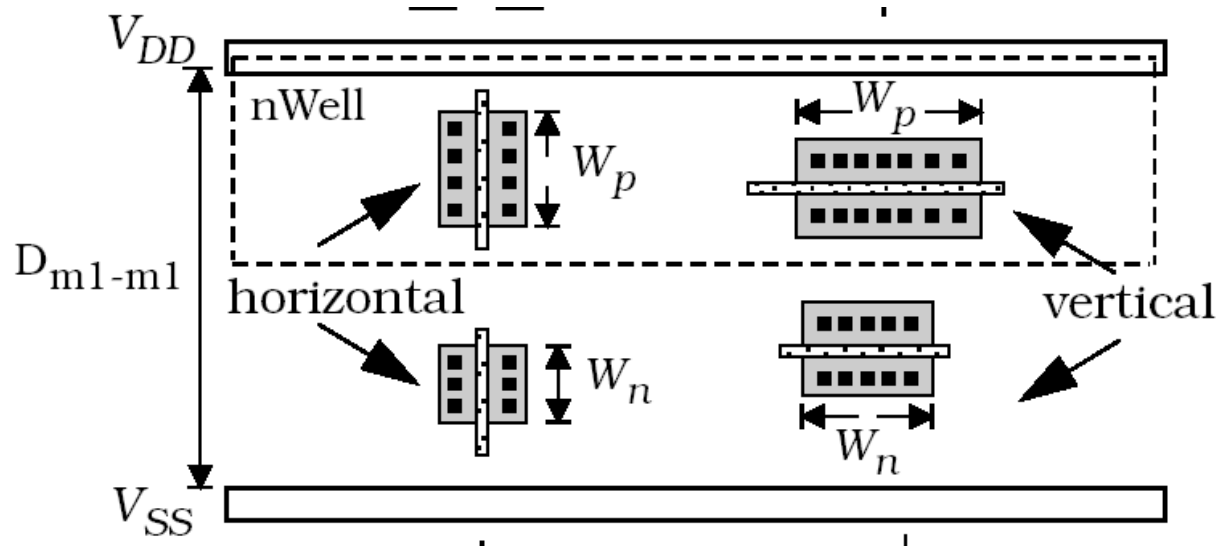
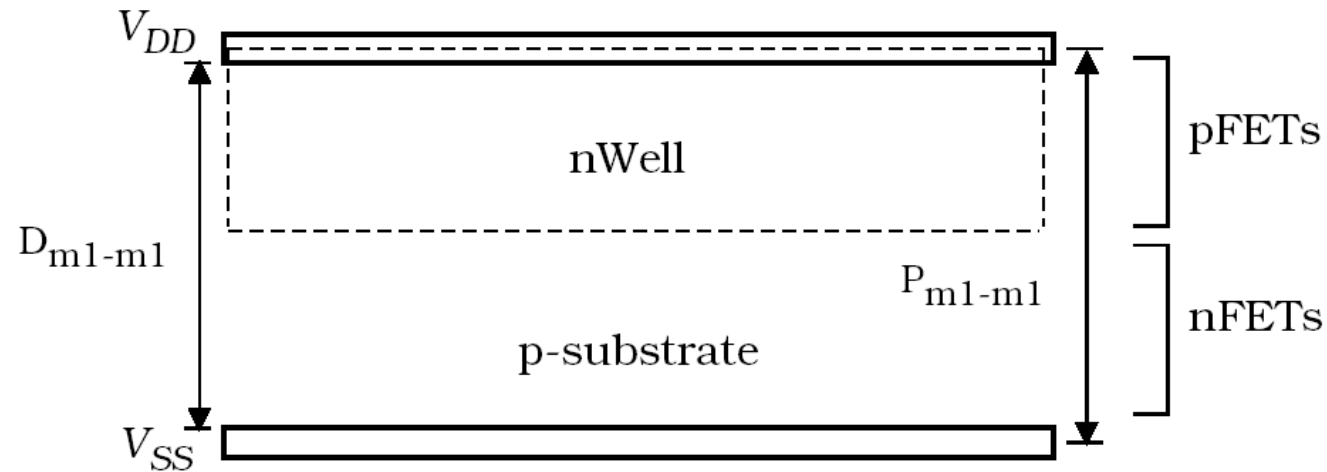
- **Circuit extraction is used for LVS, and for spice simulation of layouts**

Verification

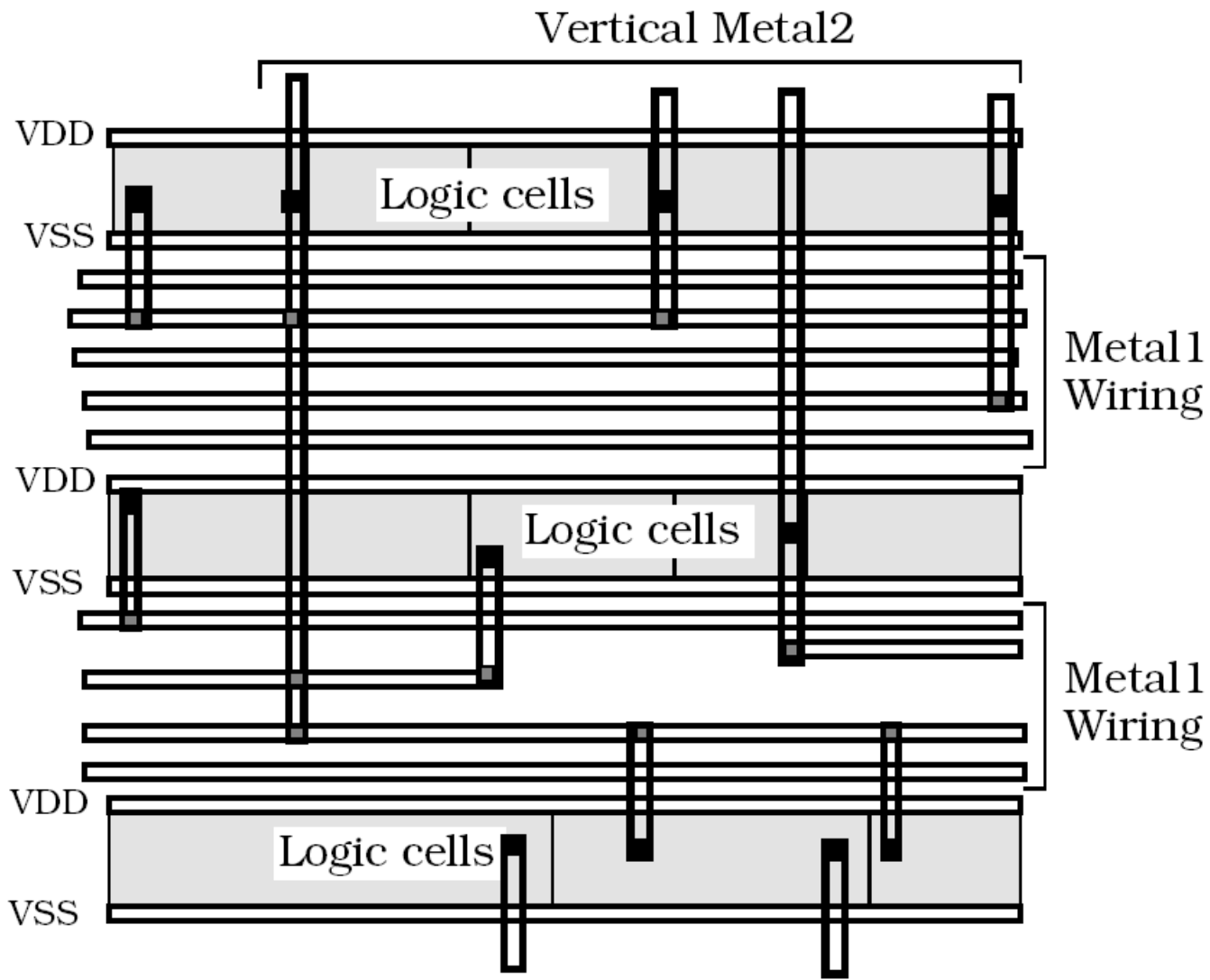
- Schematic simulation
 - Ensures functionality and provides an approximate estimate of timing
- Simulation of extracted layout
 - Ensures timing in the presence of parasitic capacitances/resistances (wires, junctions stc.)
 - Provides ‘more accurate’ estimation of timing
- Formal verification
 - Mathematically verify the functionality of the circuit from its logic level description
 - Very important for large circuits where circuit simulation will take long time

Physical Design: Logic Cells to Small Systems

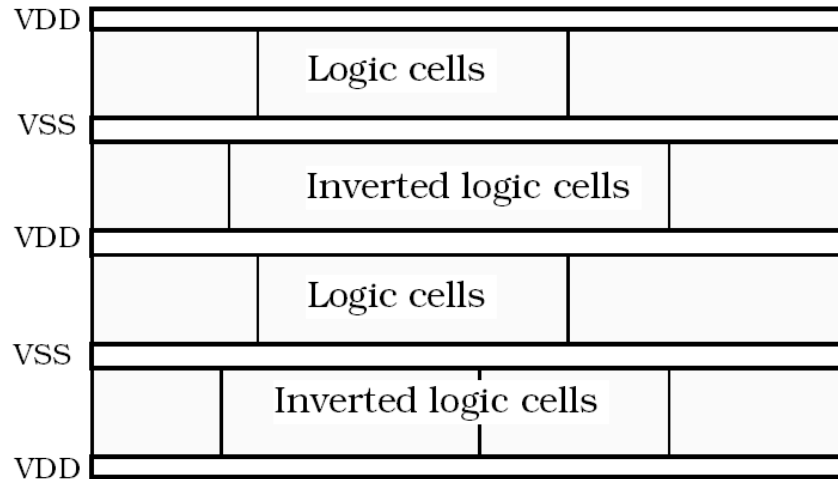
Physical Design for Large Number of Cells



Wiring channels.

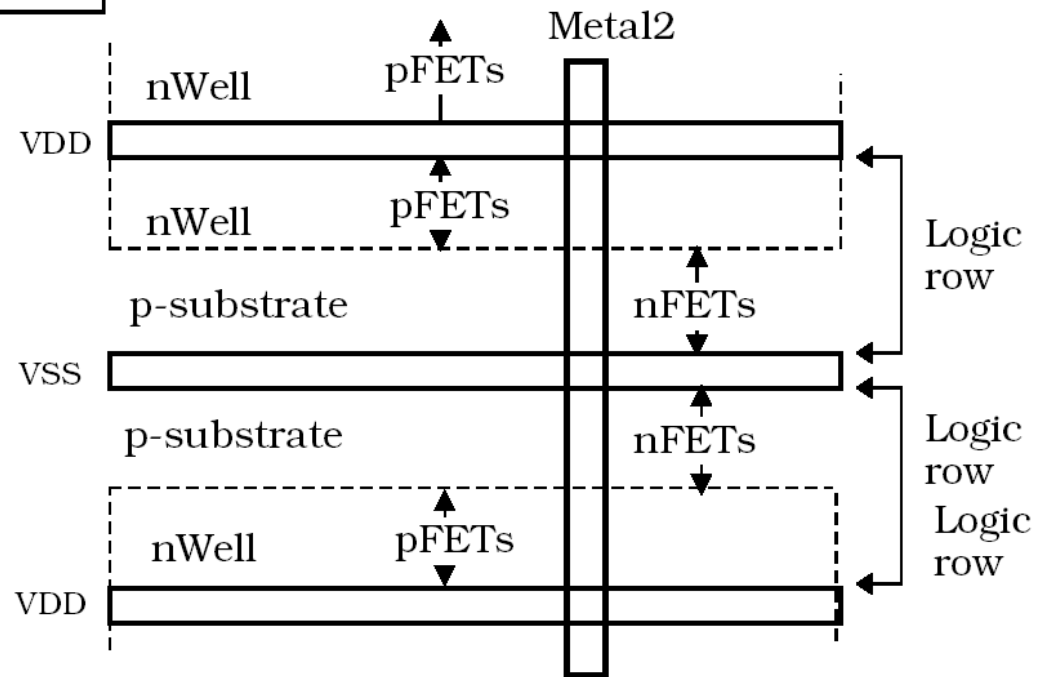


Weinberger image array.

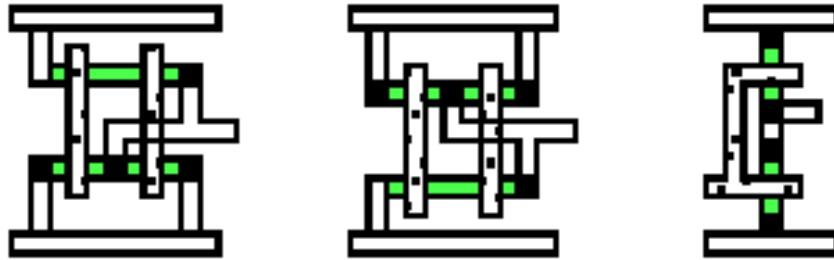


Cell placements

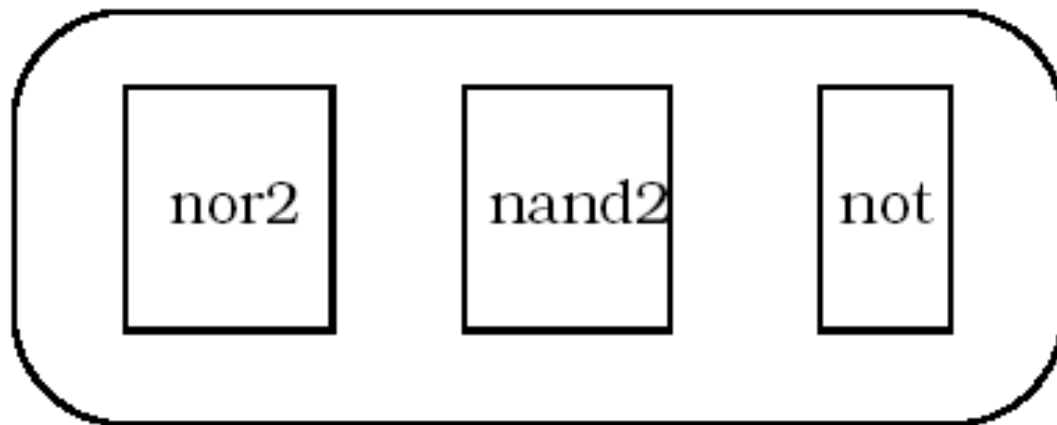
FETs



Primitive polygon-level library entries.

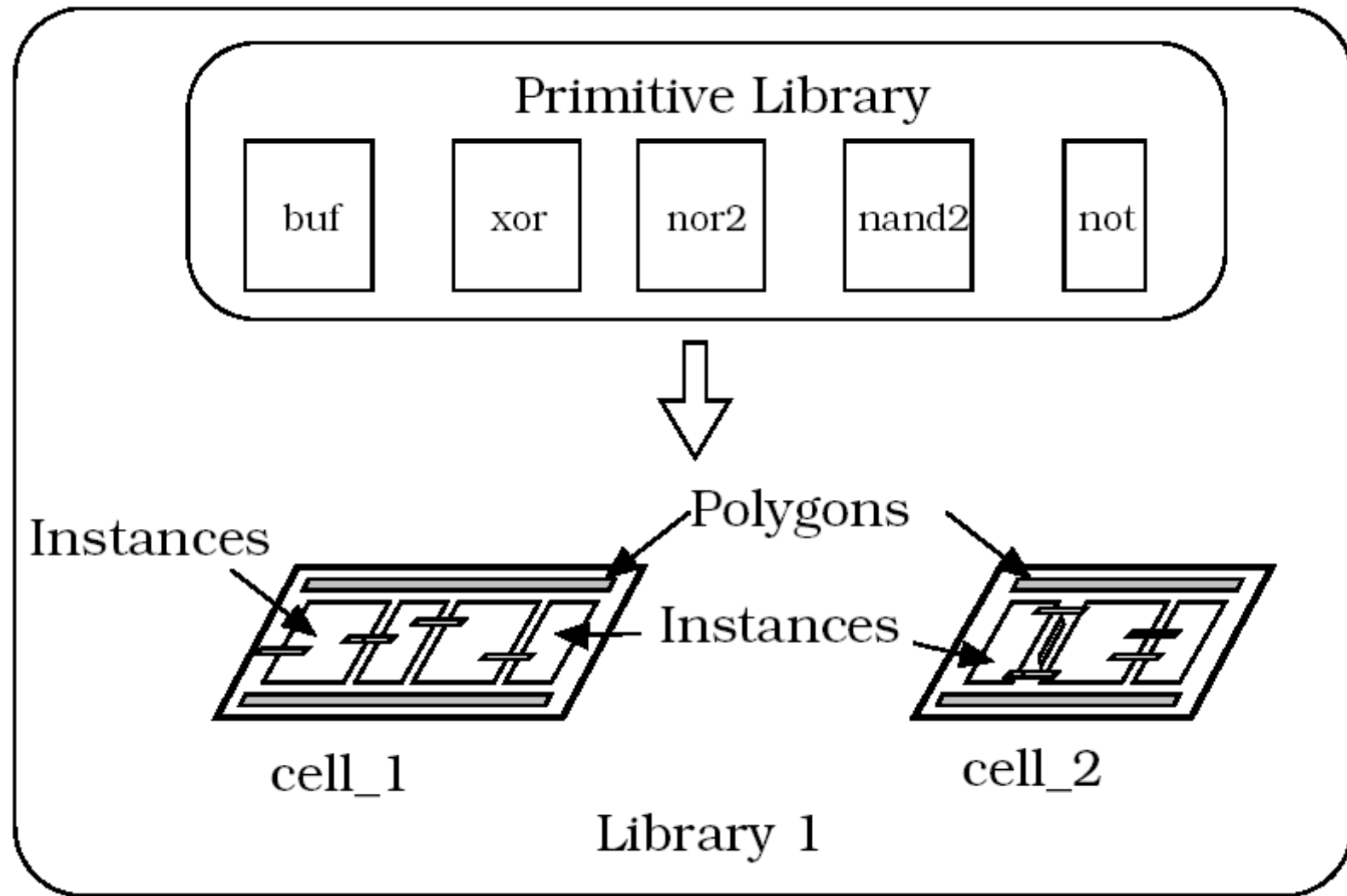


Polygon level

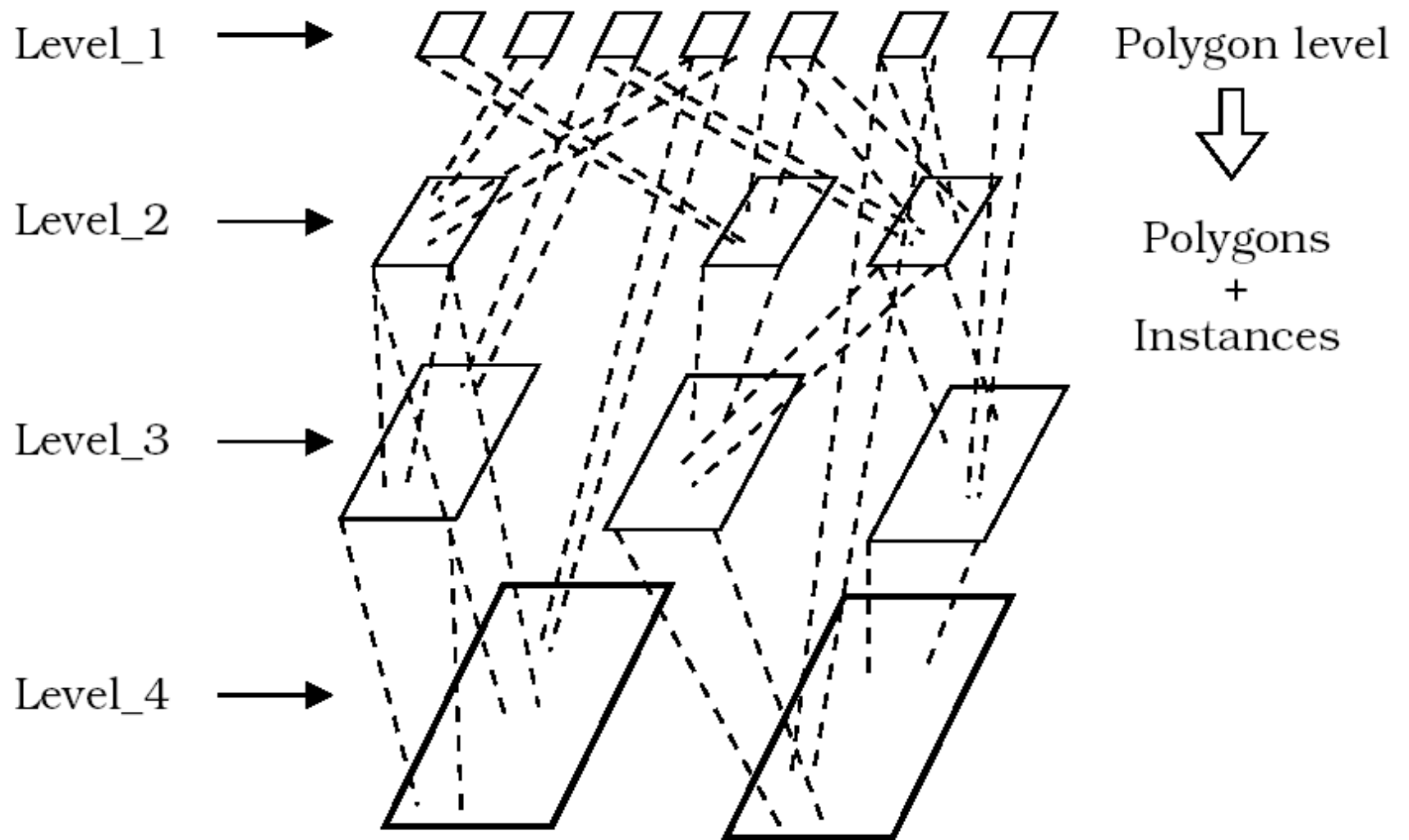


Cells in the library

Expanding the library with more complex cells.



Cell hierarchy



Large Design Layout:
Example: SRAM
Important for Project

Layout of SRAM Cell

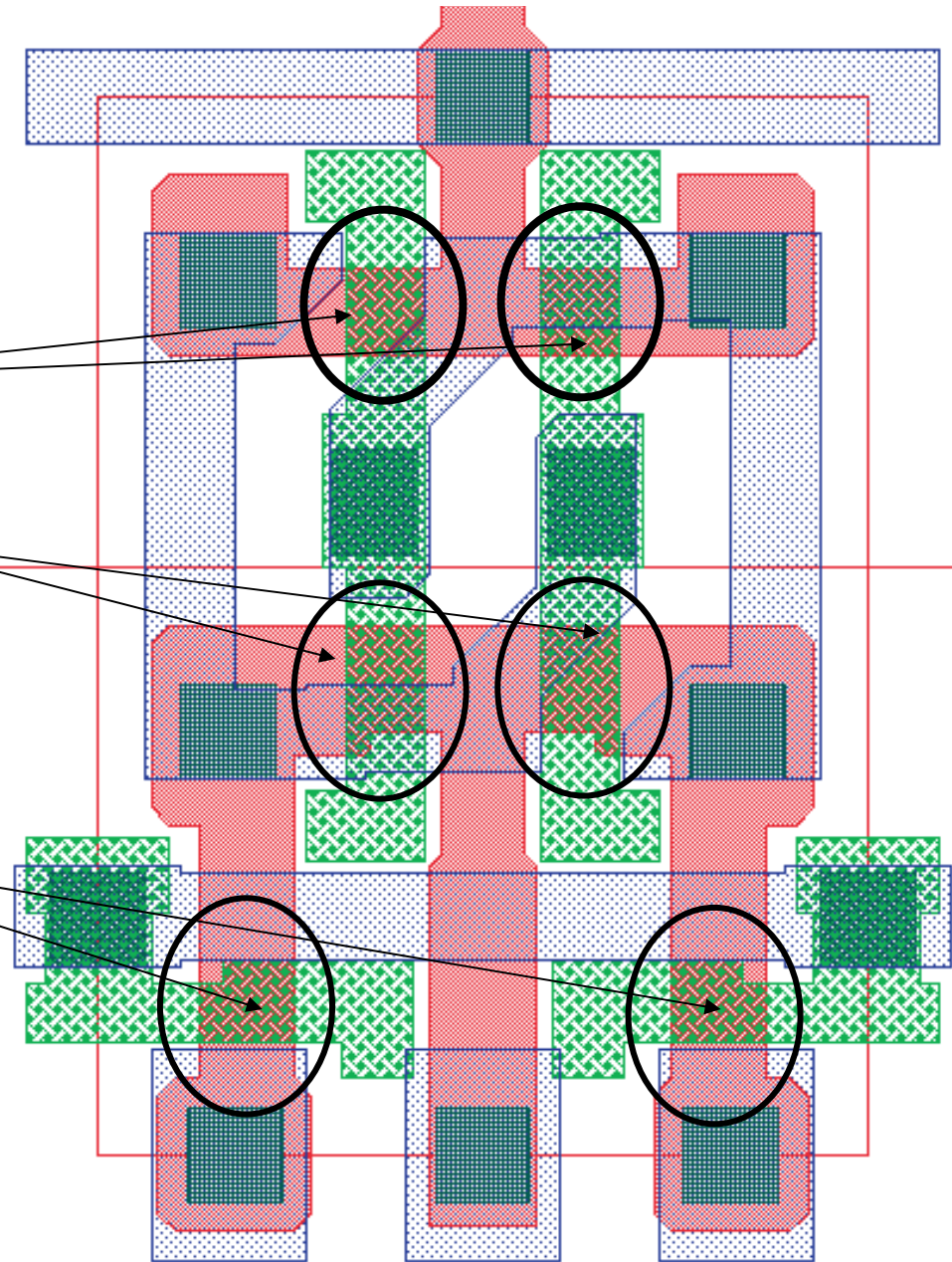
Green – PC
Red - RX

PULL - UP

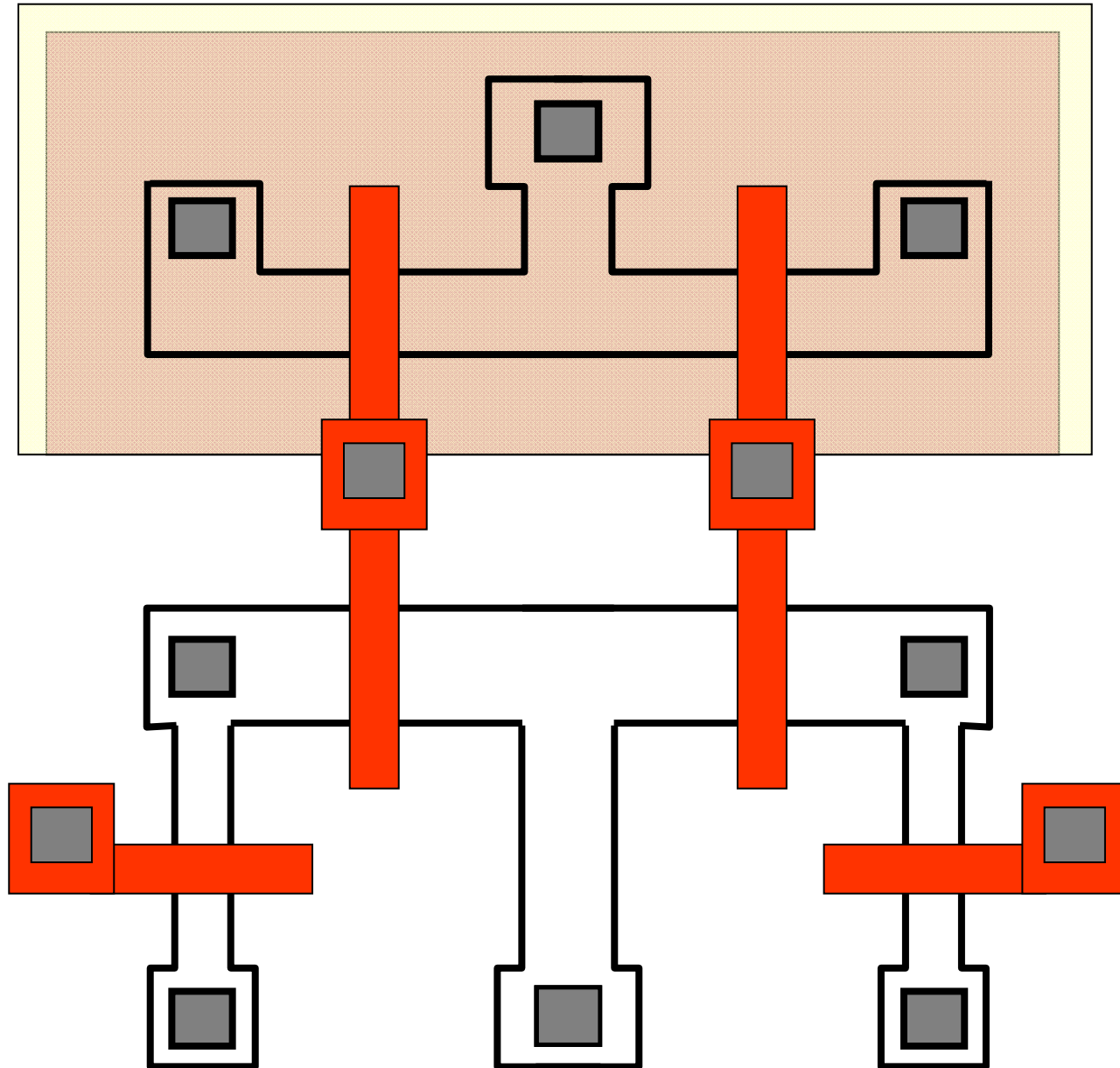
PULL - DOWN

PASS-GATE

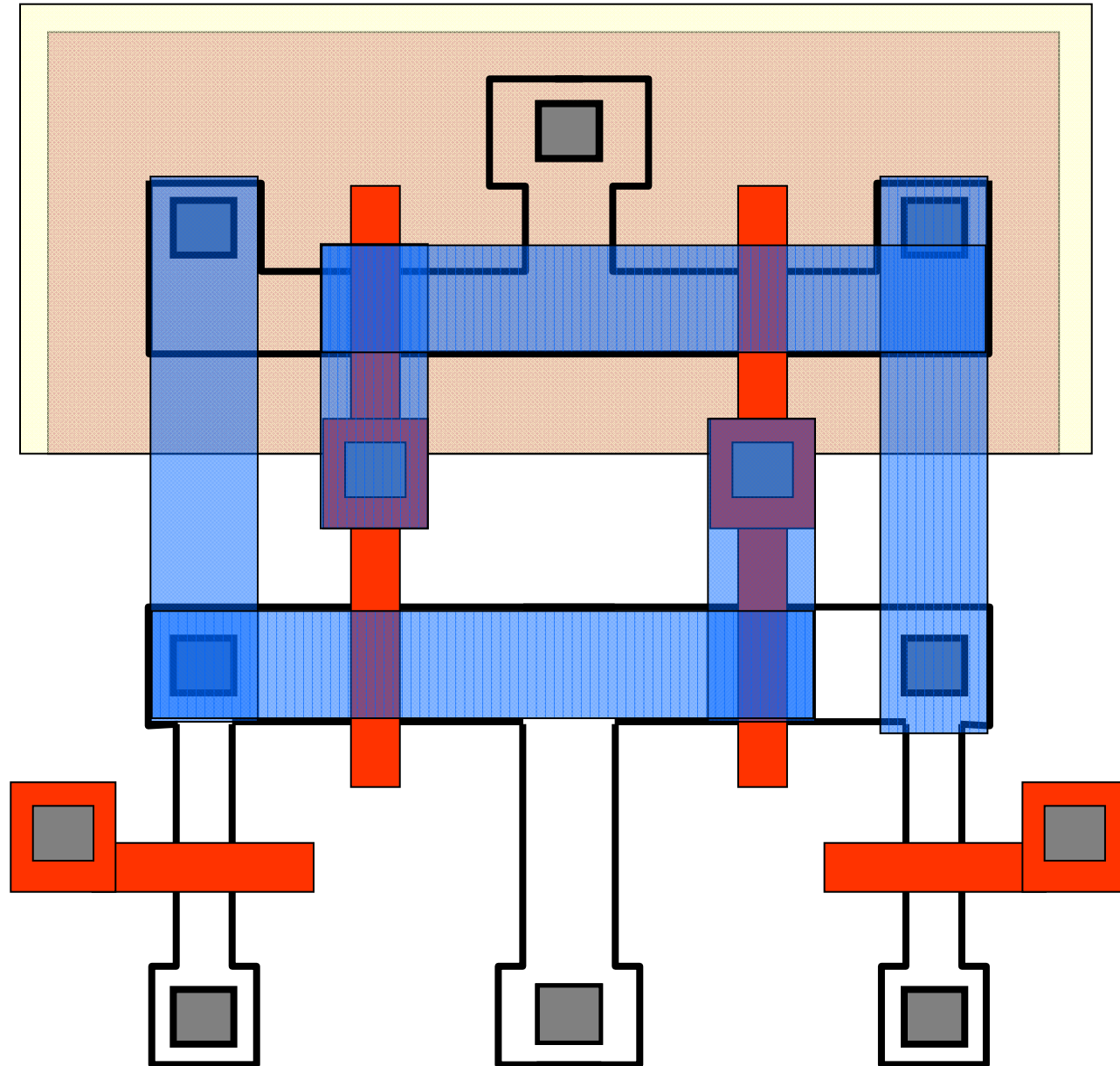
Ref.
R.W. Mann, et. al.
IBM J. R&D



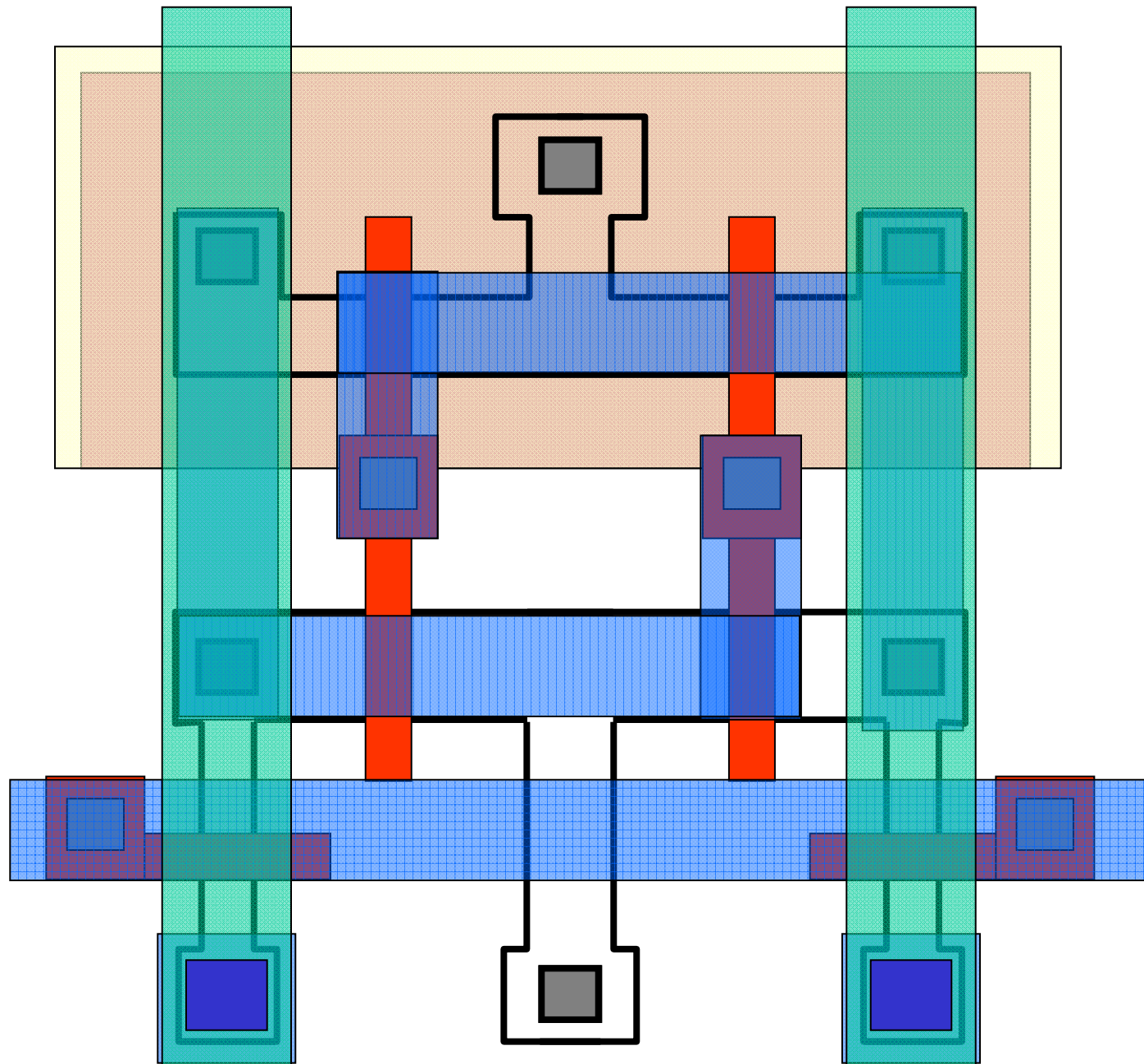
Layout of SRAM Cell



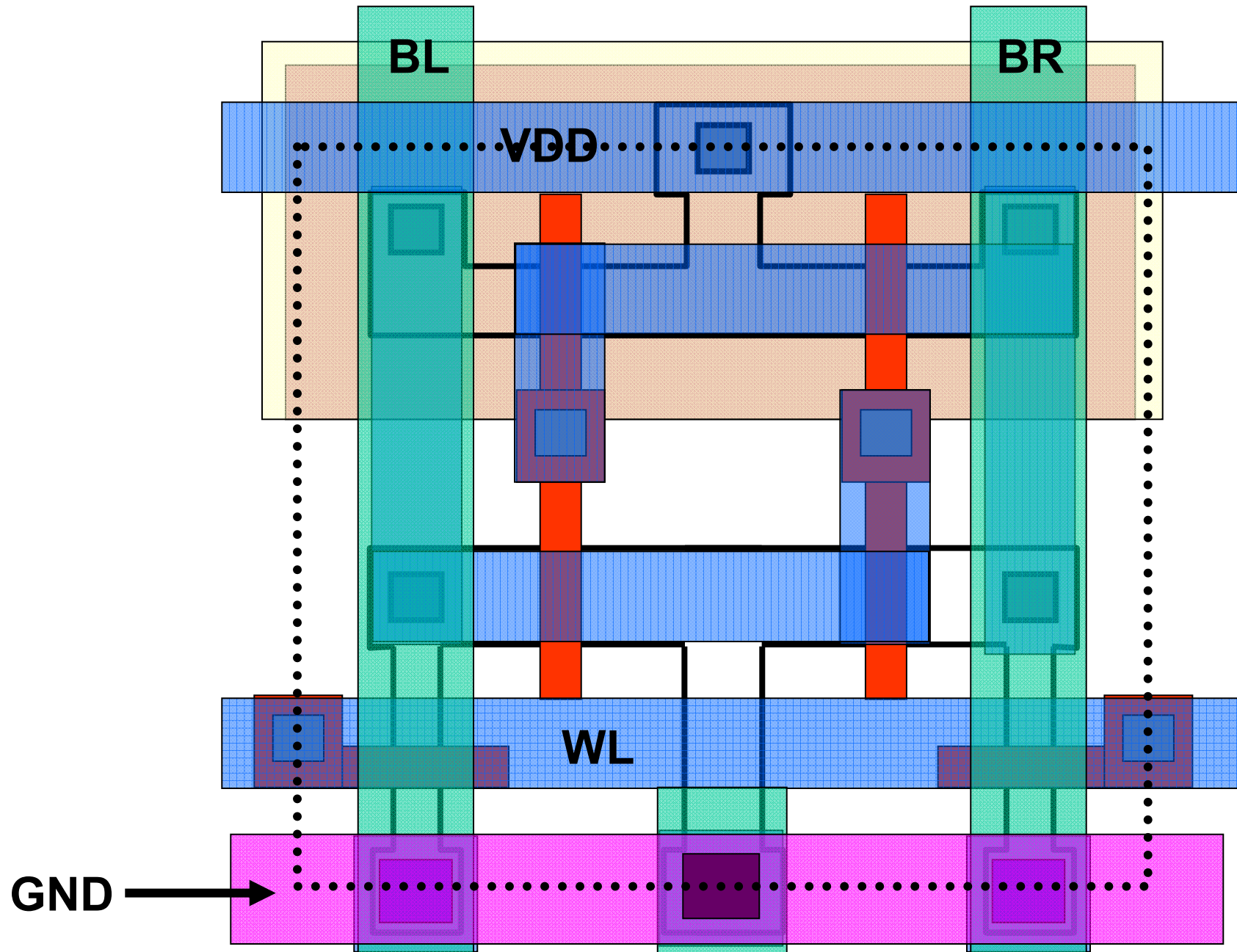
Layout of SRAM Cell



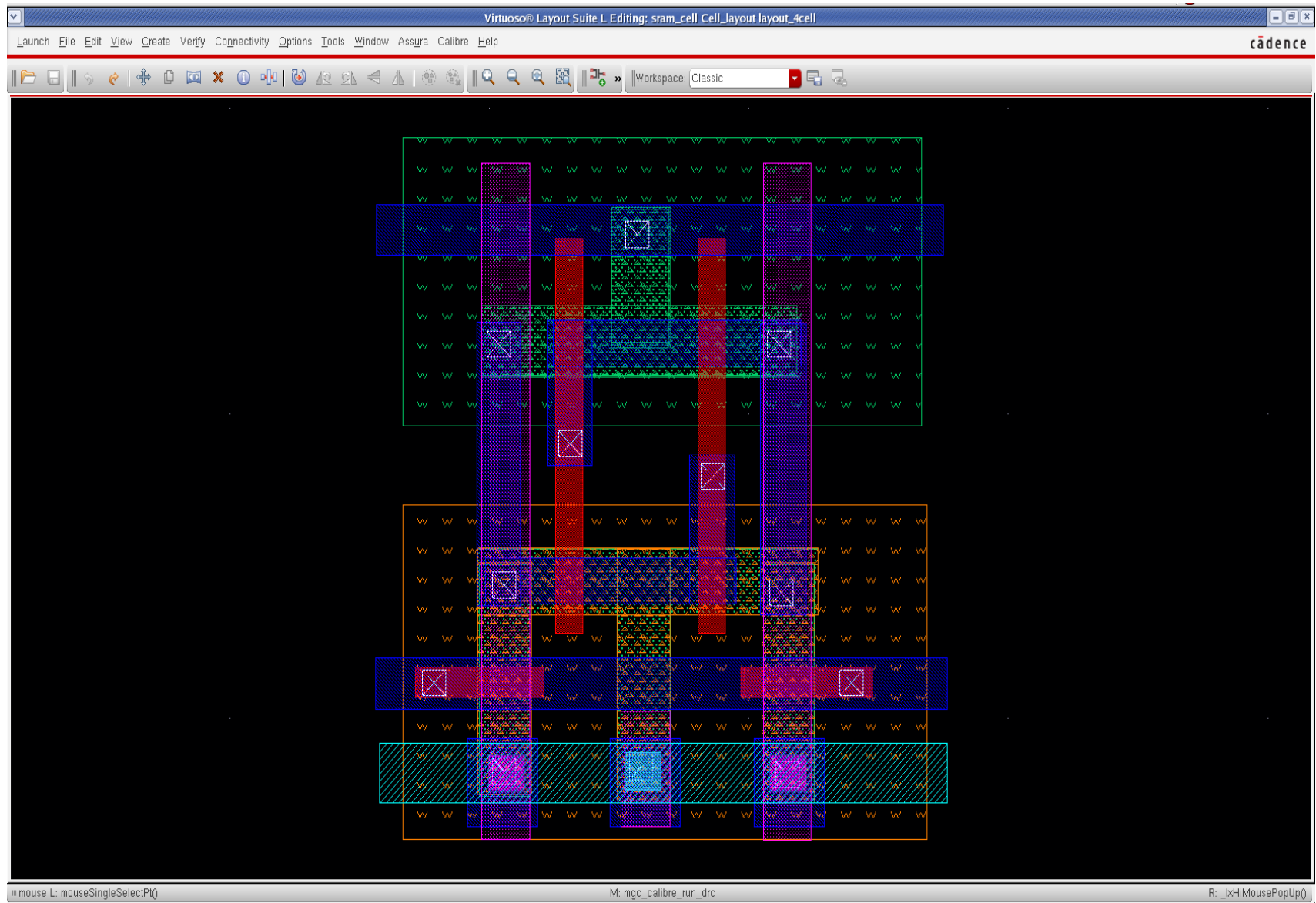
Layout of SRAM Cell

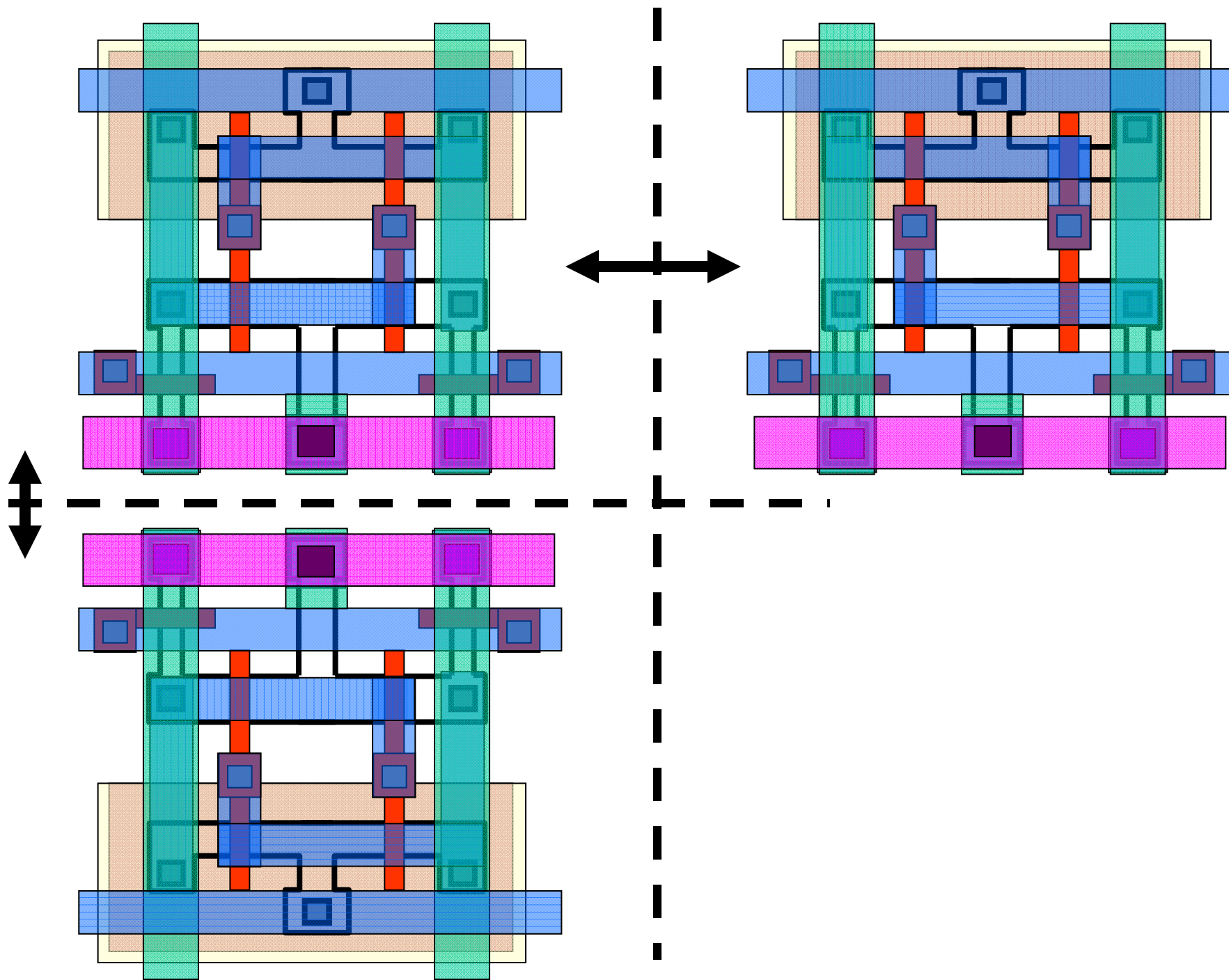


Layout of SRAM Cell

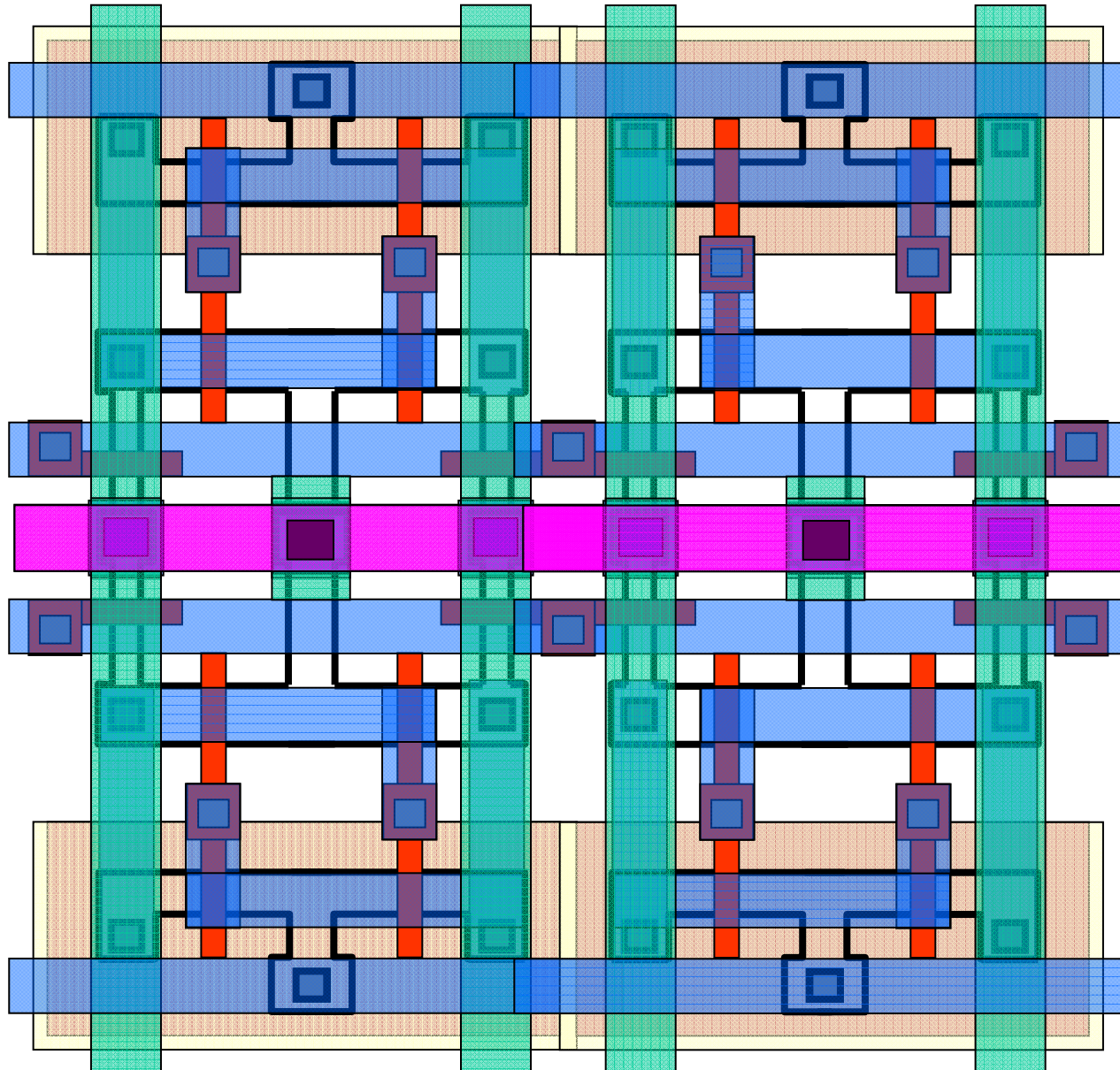


Layout of SRAM Cell

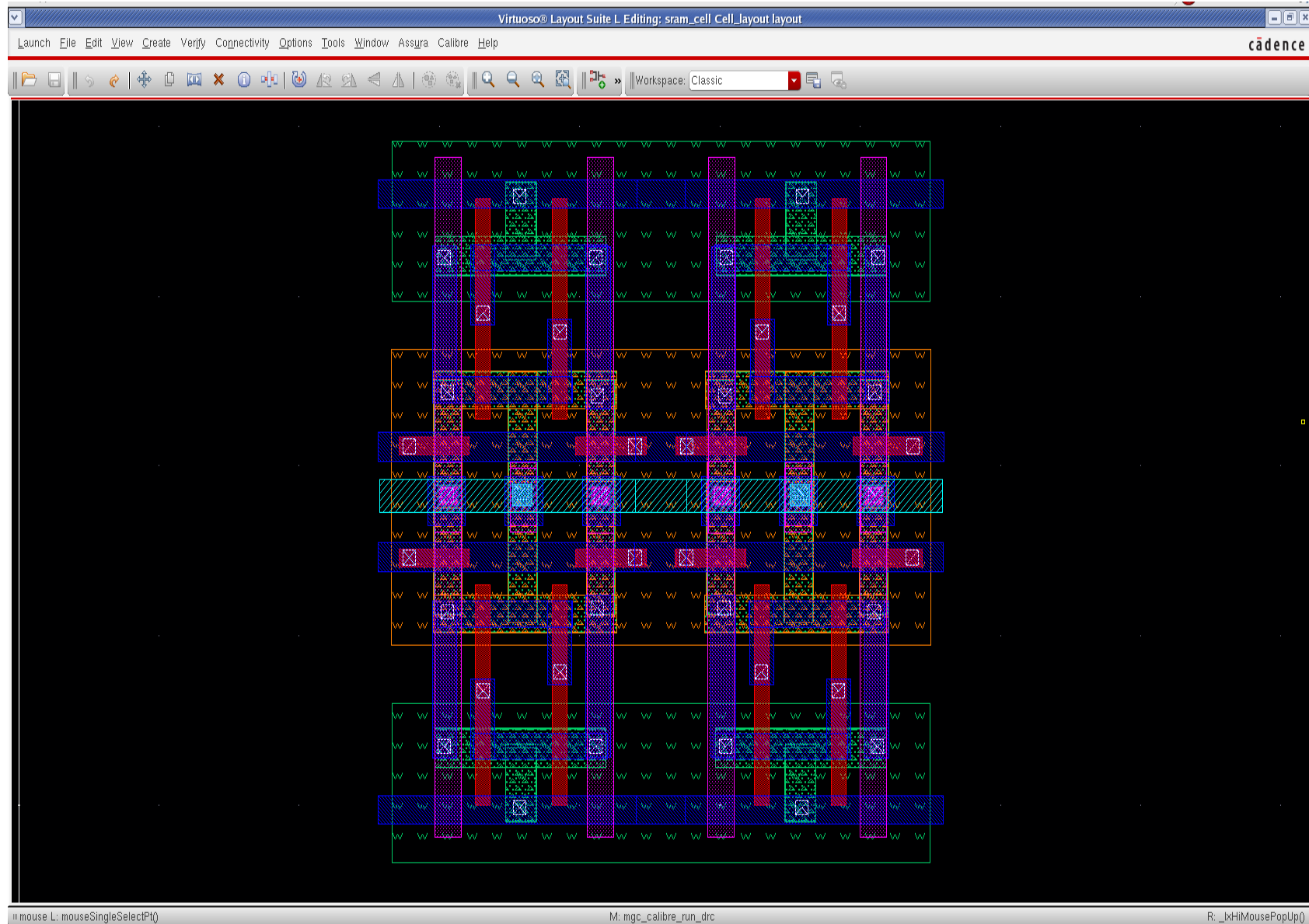




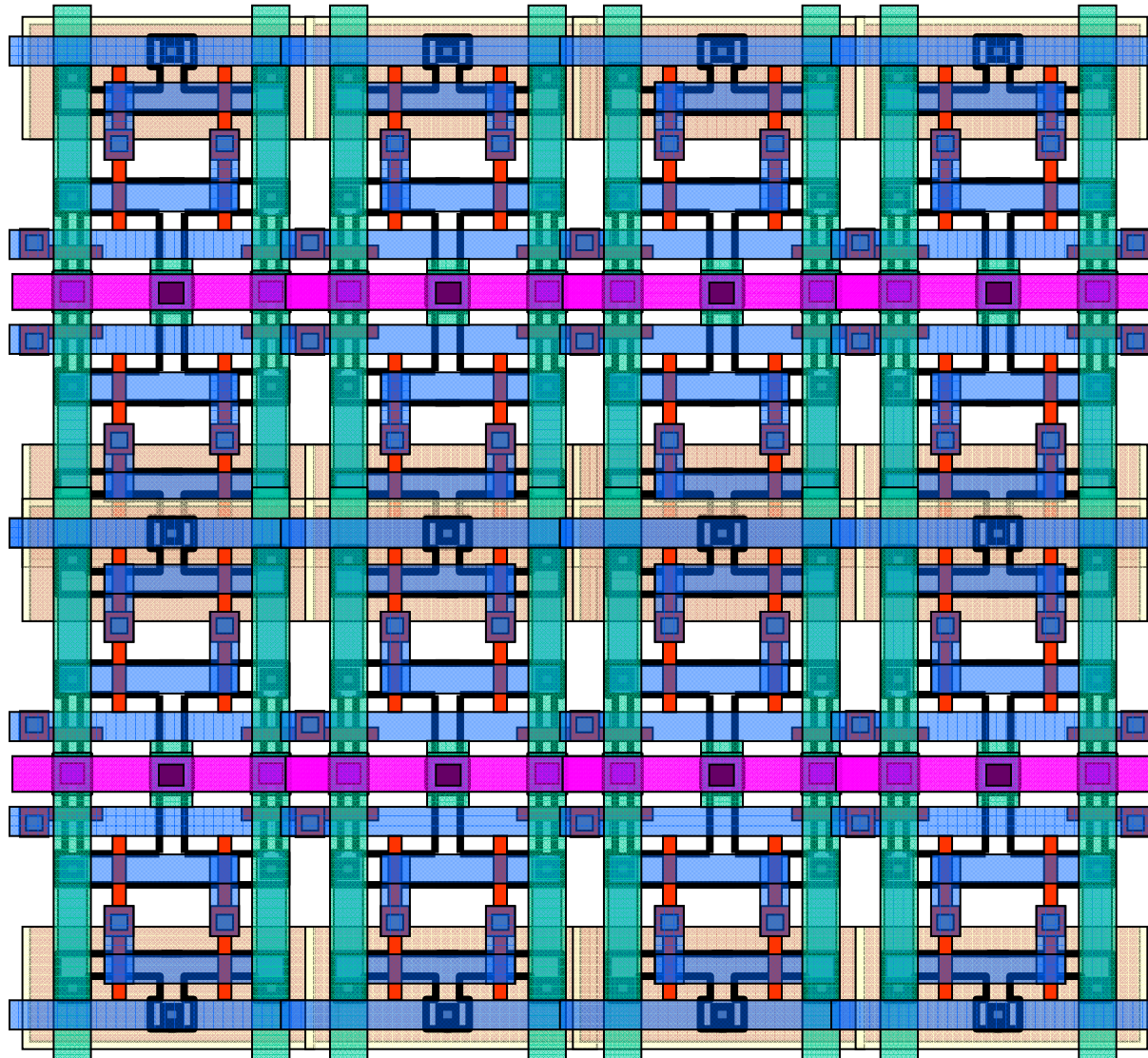
Basic 'Standard Cell' for Array – 4 Cells



Basic 'Standard Cell' for Array – 4 Cells

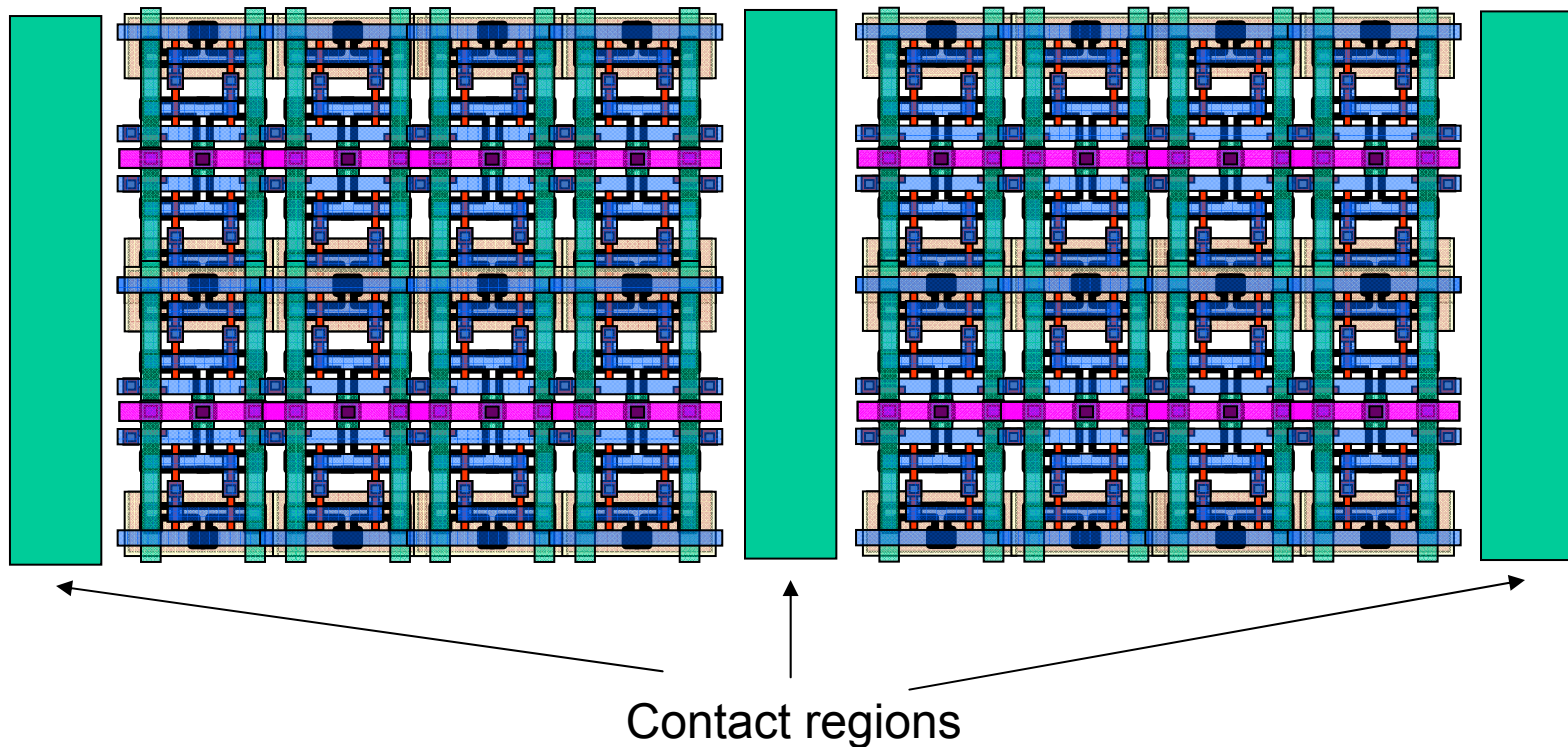


Array Construction – $4 \times 4 = 16$ Cells



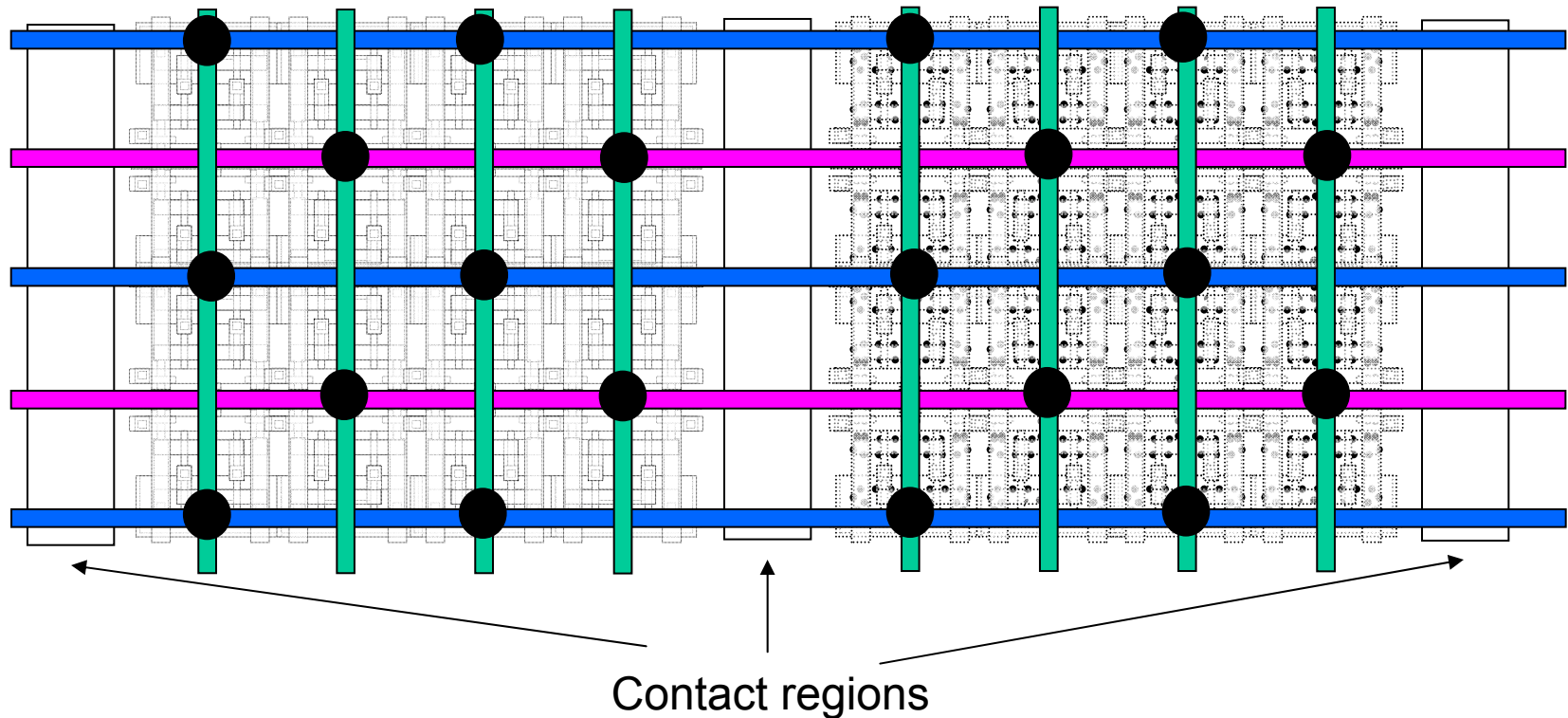
Next repeat this block for 8 x 8 array, and so on

Array Construction – Substrate/N-well contacts



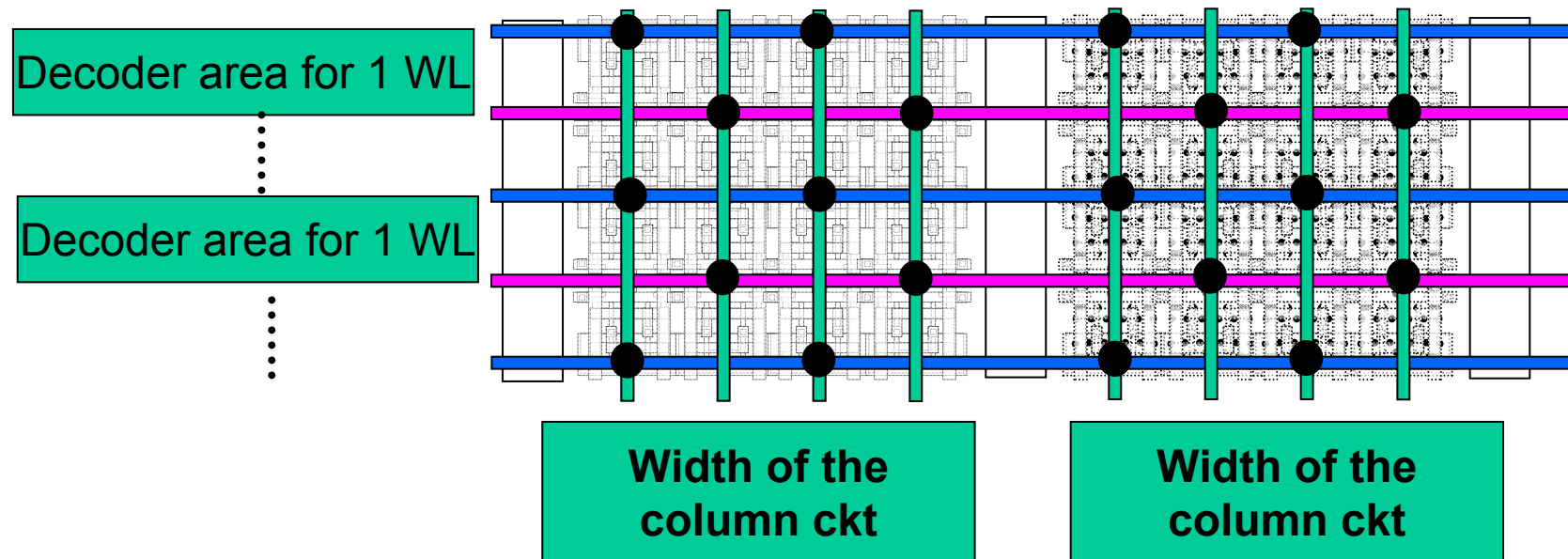
- Normally, to save area n-well and substrate contacts are not present in every SRAM cell.
- The DRC rules specifies the maximum allowable distance between a NMOS (or PMOS) device and substrate (or n-well) contact.
- In array design, normally contacts are placed only to satisfy the constraints so that area can be lower.

Array Construction – Supply Network



- Only horizontal supply and ground lines are not enough as these lines are not connected to each other
 - Lower stability and higher variability in supply network
- A network is supply is normally used with vertical lines connecting the horizontal lines

System Level Physical Design of the Array



- Each decoded bit the row decoder needs to fit within the height of the memory cell.
- Width of the column circuit need to fit the pitch of 4 columns (if using a 4 x 1 column multiplexer)